

Silicon Tracking Detectors for the LHC experiments



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Part 1:

1. Tracking at the LHC experiments
2. The CMS and Atlas silicon tracker

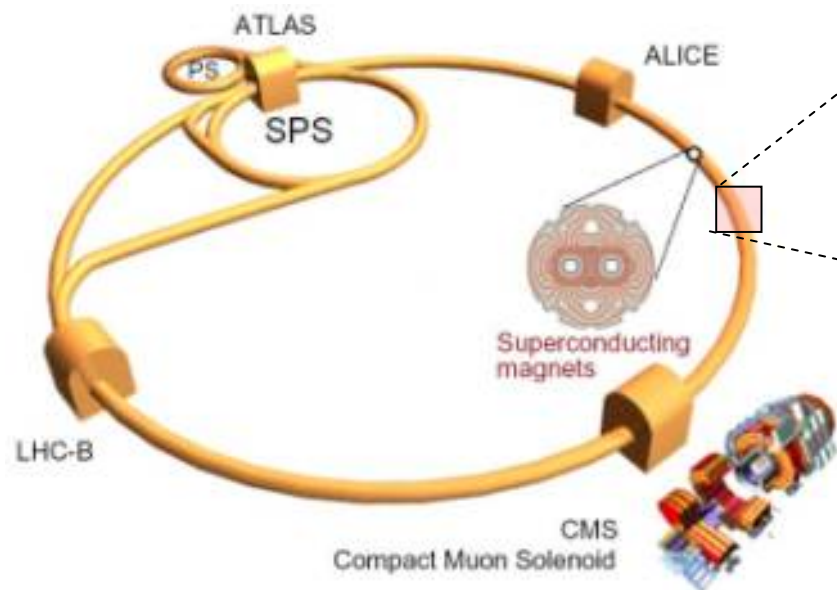
Part 2:

1. Performance degradation with irradiation
2. Physical modelling of radiation damage
3. Model applications

Experiments at the LHC



Two super-conducting rings
in the LEP tunnel



	Beam	Energy	Luminosity
LEP	e^+e^-	200 GeV	$10^{32} \text{ cm}^{-2}\text{s}^{-1}$
LHC	p-p	14 TeV	$10^{34} \text{ cm}^{-2}\text{s}^{-1}$
	Pb-Pb	1312 TeV	$10^{27} \text{ cm}^{-2}\text{s}^{-1}$

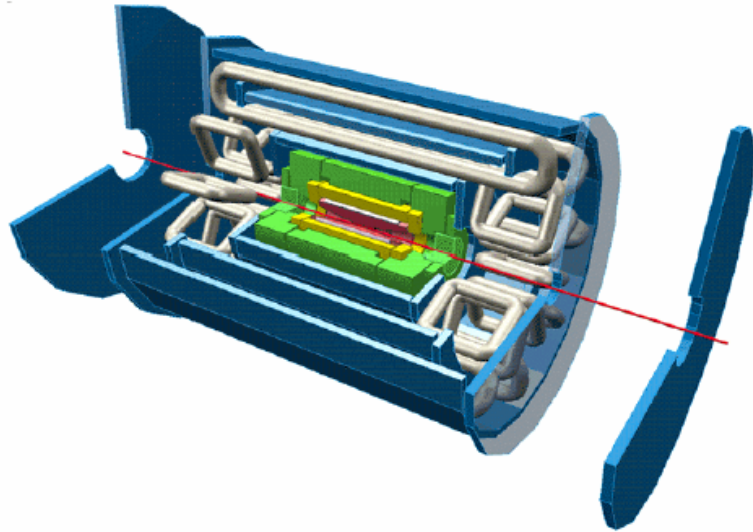
Experiments at LHC:

- ATLAS** A Toroidal LHC ApparatuS. (Study of Proton-Proton collisions)
- CMS** Compact Muon Solenoid. (Study of Proton-Proton collisions)
- ALICE** A Large Ion Collider Experiment. (Study of Ion-Ion collisions)
- LHCb** (Study of CP violation in B-meson decays at the LHC collider)

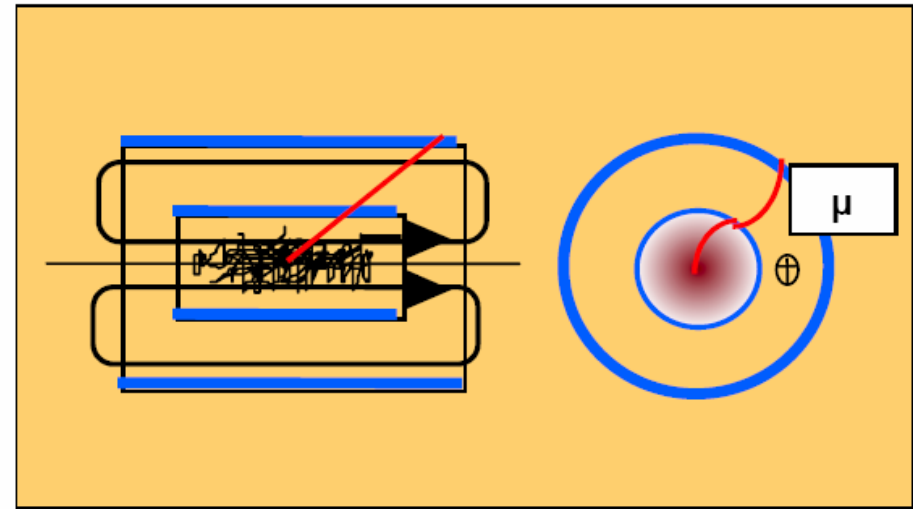
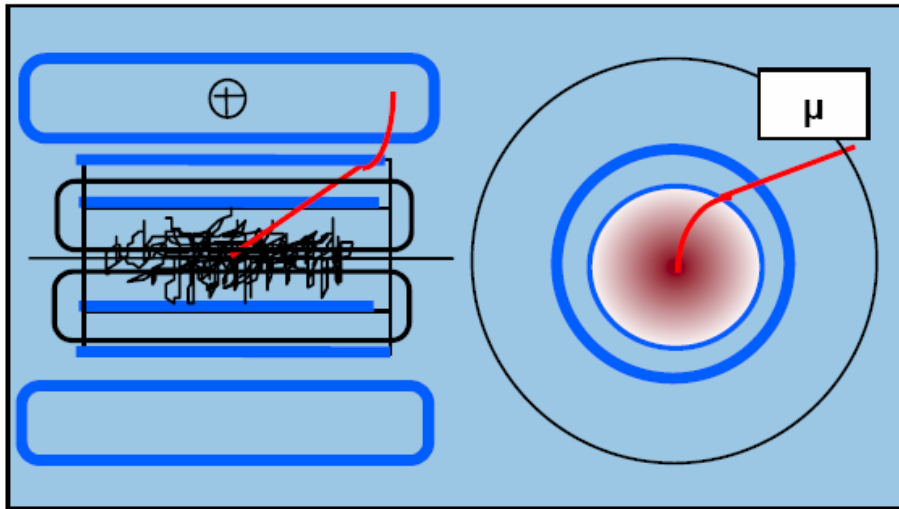
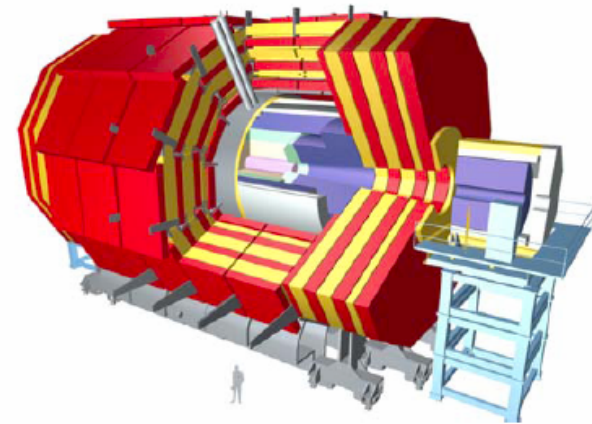
Atlas and CMS



ATLAS A Toroidal LHC ApparatuS



CMS Compact Muon Solenoid



Tracking requirements at LHC



- **Efficient and robust pattern recognition:**
 - High speed to resolve bunch crossing
 - Fine granularity to resolve nearby tracks
- **Reconstruct narrow heavy objects:**
 - 1-2% P_T resolution at 100 GeV
- **Tag b's and tau's through secondary vertices**
- **Radiation hardness of all components**
 - Up to 3×10^{14} $n_{eq}/\text{cm}^2/\text{year}$ at full luminosity in the innermost layers

Minimum bias events



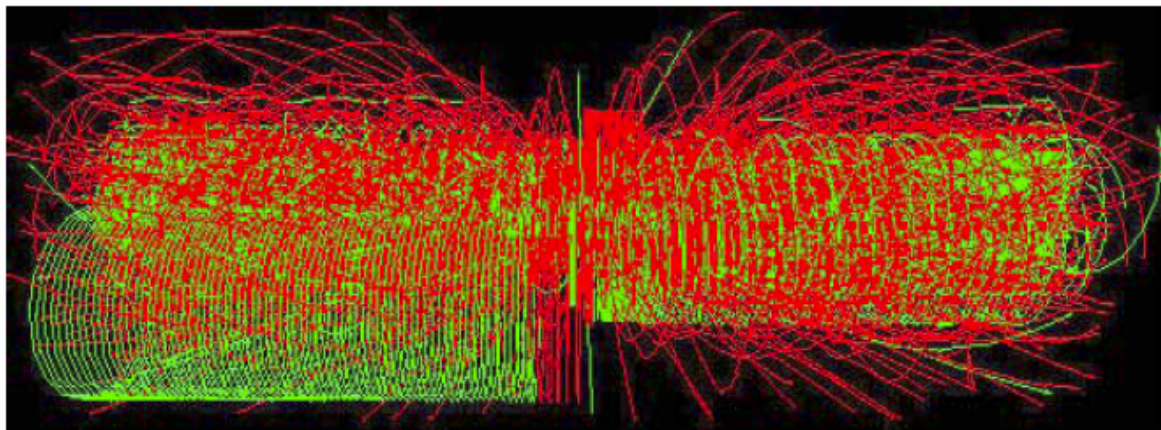
Luminosity = $10^{34} \text{ cm}^{-2}\text{s}^{-1} = 10^7 \text{ mb}^{-1}\text{Hz}$

Interaction rate = $10^7 \times 80 = 8 \times 10^8 \text{ Hz}$

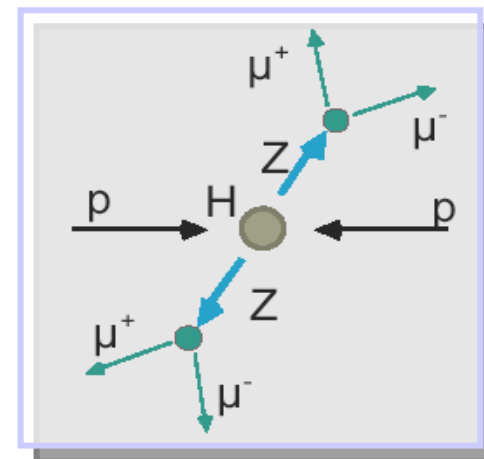
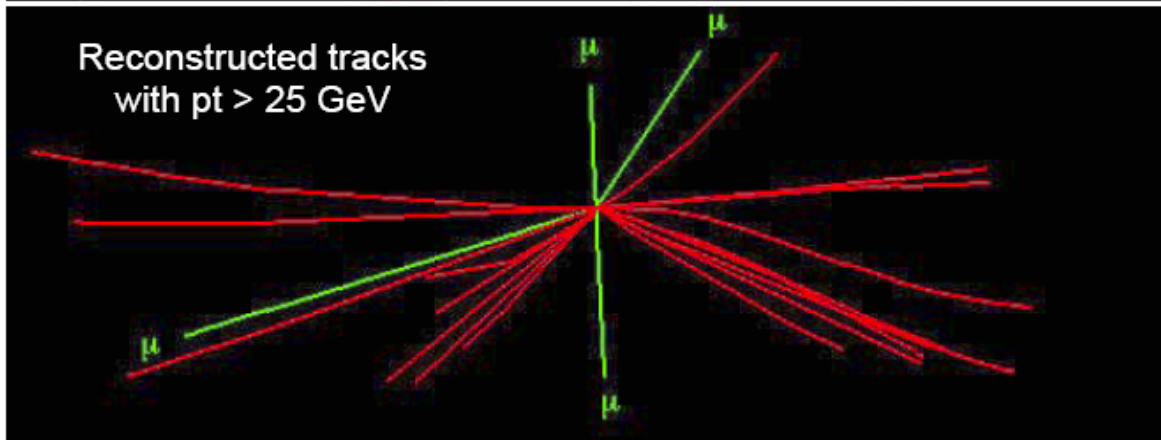
Interactions/crossing = 20

$\sigma(\text{pp}) = 80 \text{ mb}$ at 14 TeV

Bunch crossing = 25 ns = $2.5 \times 10^{-8} \text{ s}$



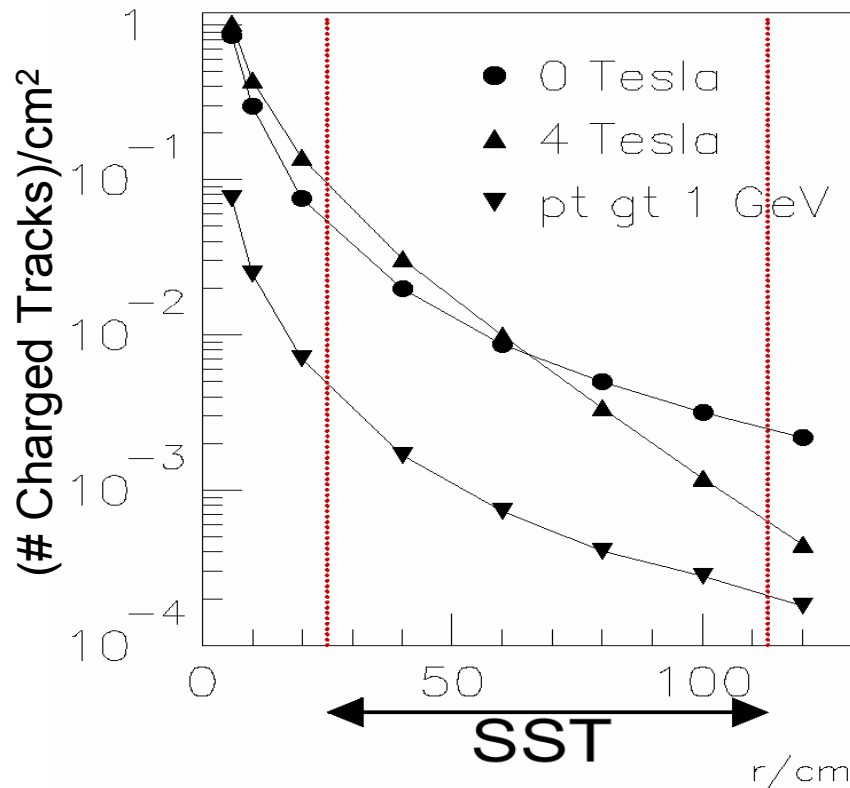
Higgs event
+
~25 minimum bias events



Detector occupancy



- Efficient and robust reconstruction with few hits requires occupancy below few %
- At small radii need cell size $\ll 1\text{cm}^2$ and fast ($\sim 25\text{ns}$) shaping time.
- This condition is relaxed at large radii



Example: CMS Tracker

Innermost layers:

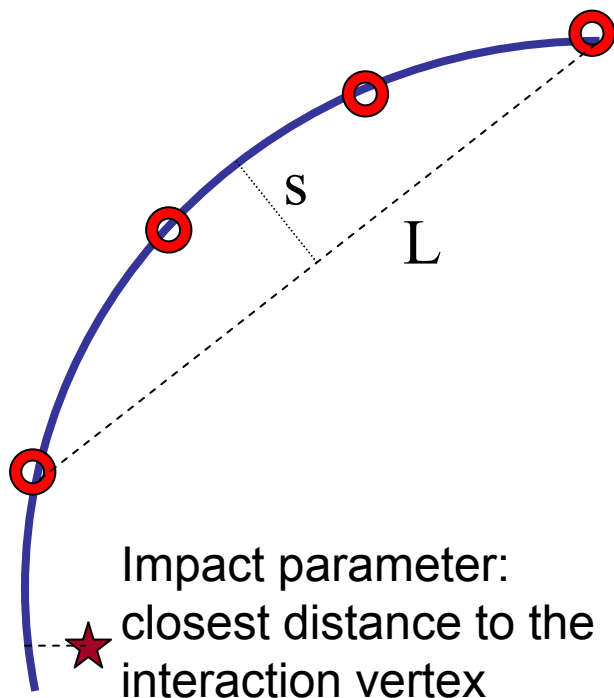
Pixels - Size=100x150 μm^2

Strip length ranges from
**10cm in the inner layers to
20cm in the outer layers**

Pitch ranges from
**80 μm in the inner layers to
 $\sim 200\mu\text{m}$ in the outer layers**



Detector channels = $\mathcal{O}(10^7)$



$P \sim$ radius of curvature of track
 $\sim 1 / \text{Sagitta}$

Goal:

$\Delta P_t / P_t \sim 0.1 \cdot P_t$ (P_t in TeV)
 allows to reconstruct $Z \rightarrow \mu + \mu^-$ with
 $\Delta m_Z < 2 \text{ GeV}$ up to $P_t \sim 500 \text{ GeV}$

Example:

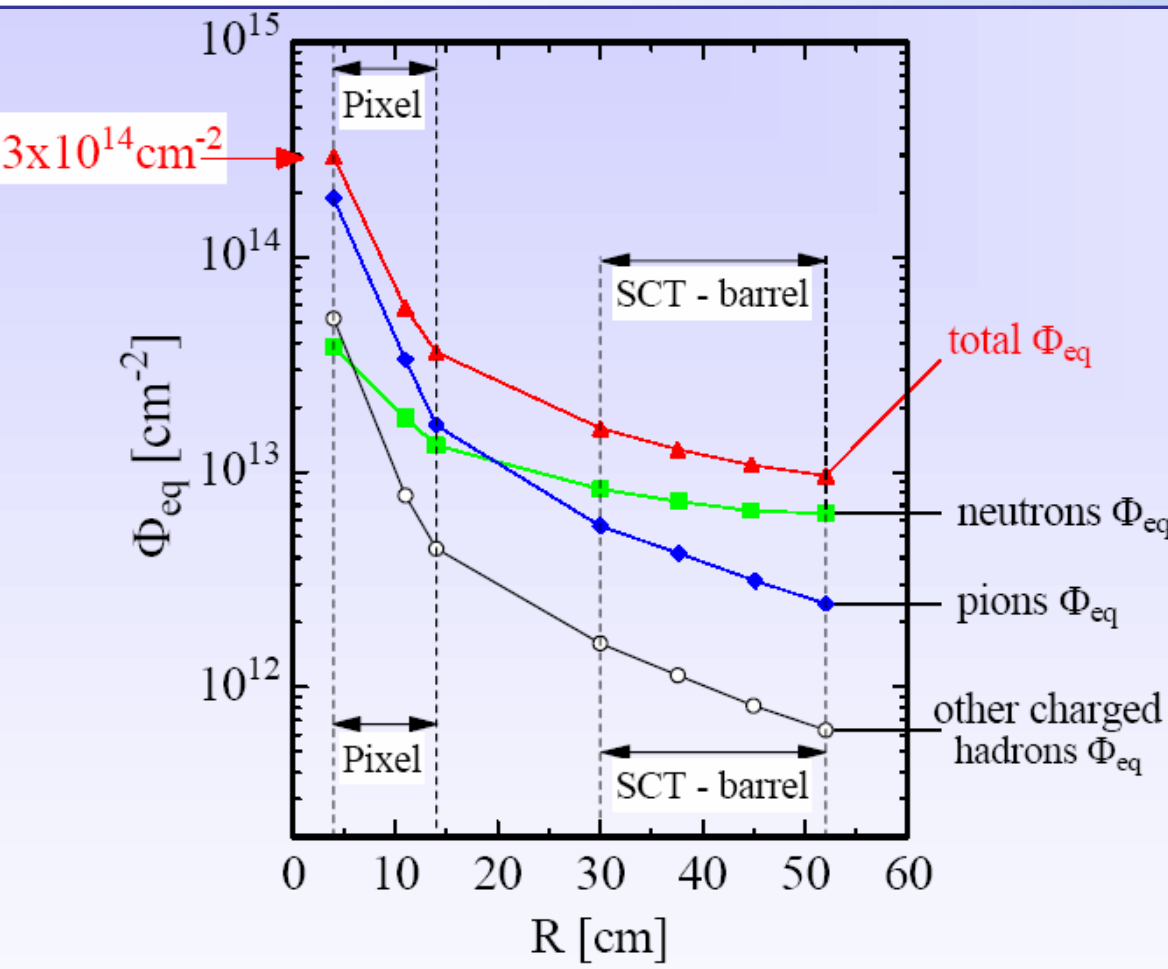
Twelve measurement layers
 Spatial resolution = $(\text{Pitch} / \sqrt{12})$
 Radius = 110 cm

$$\frac{\Delta p}{p} \approx 0.12 \left(\frac{\text{pitch}}{100 \mu\text{m}} \right)^1 \left(\frac{1.1\text{m}}{L} \right)^2 \left(\frac{4T}{B} \right)^1 \left(\frac{p}{1\text{TeV}} \right)$$

Result:

Pitch in the $r\phi$ direction: around $100 \mu\text{m}$
 Spatial resolution $\sim 20\text{-}40 \mu\text{m}$

Radiation hardness



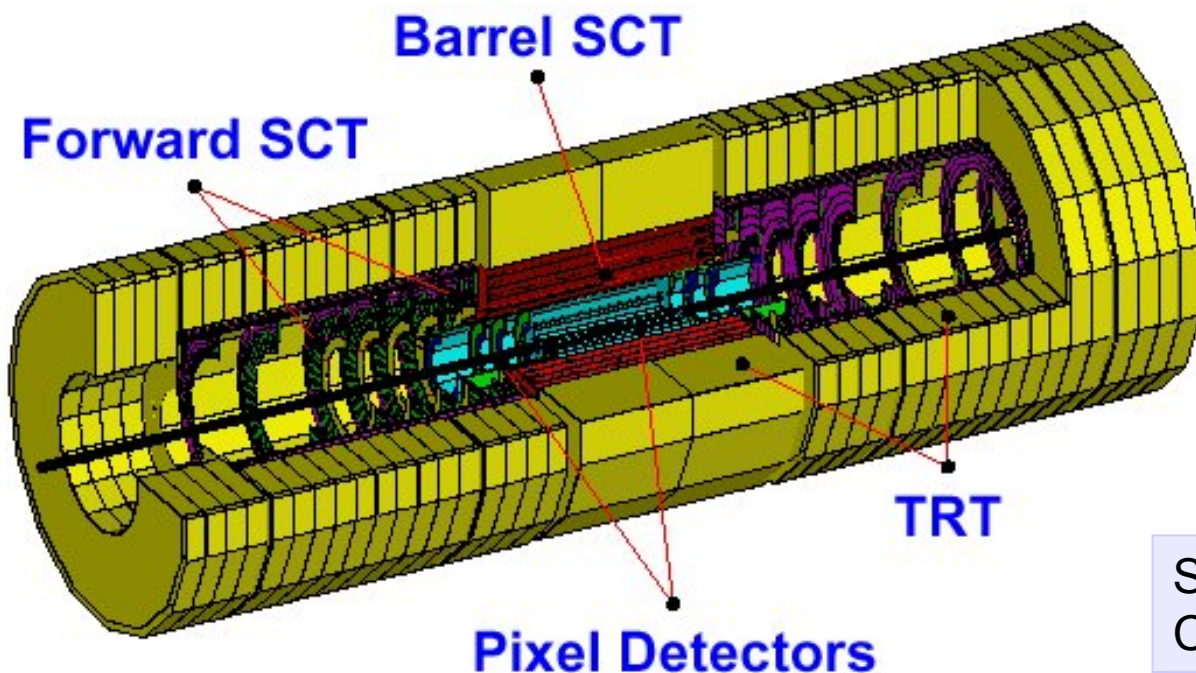
Fluence per year at full luminosity

$$\sigma_{\text{pp}}^{\text{inelastic}} = 80 \text{ mb}$$

$$\mathcal{L} = 10^{34} \text{ cm}^{-2}\text{s}^{-1}$$

- **4 cm layer $\Phi=3 \times 10^{14} \text{ n/cm}^2/\text{yr}$**
- Fluence decreases quadratically with the radius
- **Pixel detectors = 4-15 cm mostly pion irradiation**
- **Strip detectors = 20-110 cm mostly neutron irradiation**

What is the sensors response after a few years of operation?



Solenoidal field = 2 T
Calorimeters outside solenoid

- The Inner Detector (ID) is organized into:
 - Pixels ($\sim 8 \times 10^7$ channels)
 - Silicon Tracker (SCT) ($\sim 6 \times 10^6$ channels)
 - Transition Radiation Tracker (TRT) ($\sim 4 \times 10^5$ channels)

Atlas Semi-Conductor Tracker

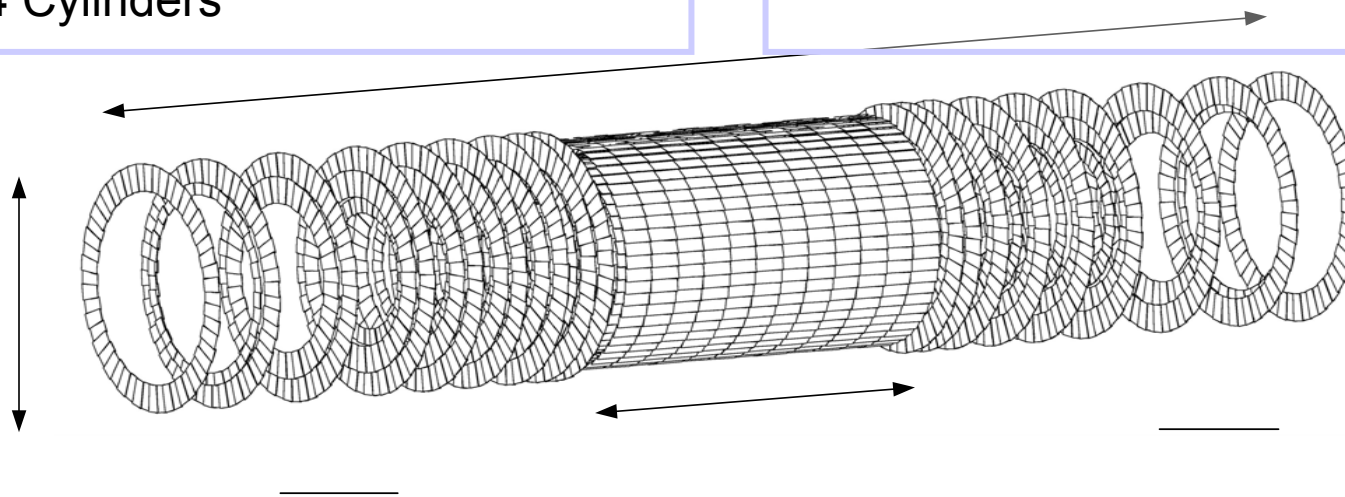


Barrel

- 34.4 m² of silicon
- ~3.2 x 10⁶ channels
- 2112 barrel modules (1 type)
- Space point resolution:
 - $r\phi \sim 16$ mm
 - $Z \sim 580$ mm
- Coverage: $|\eta| < 1.1$ to 1.4
- 4 Cylinders

Forward

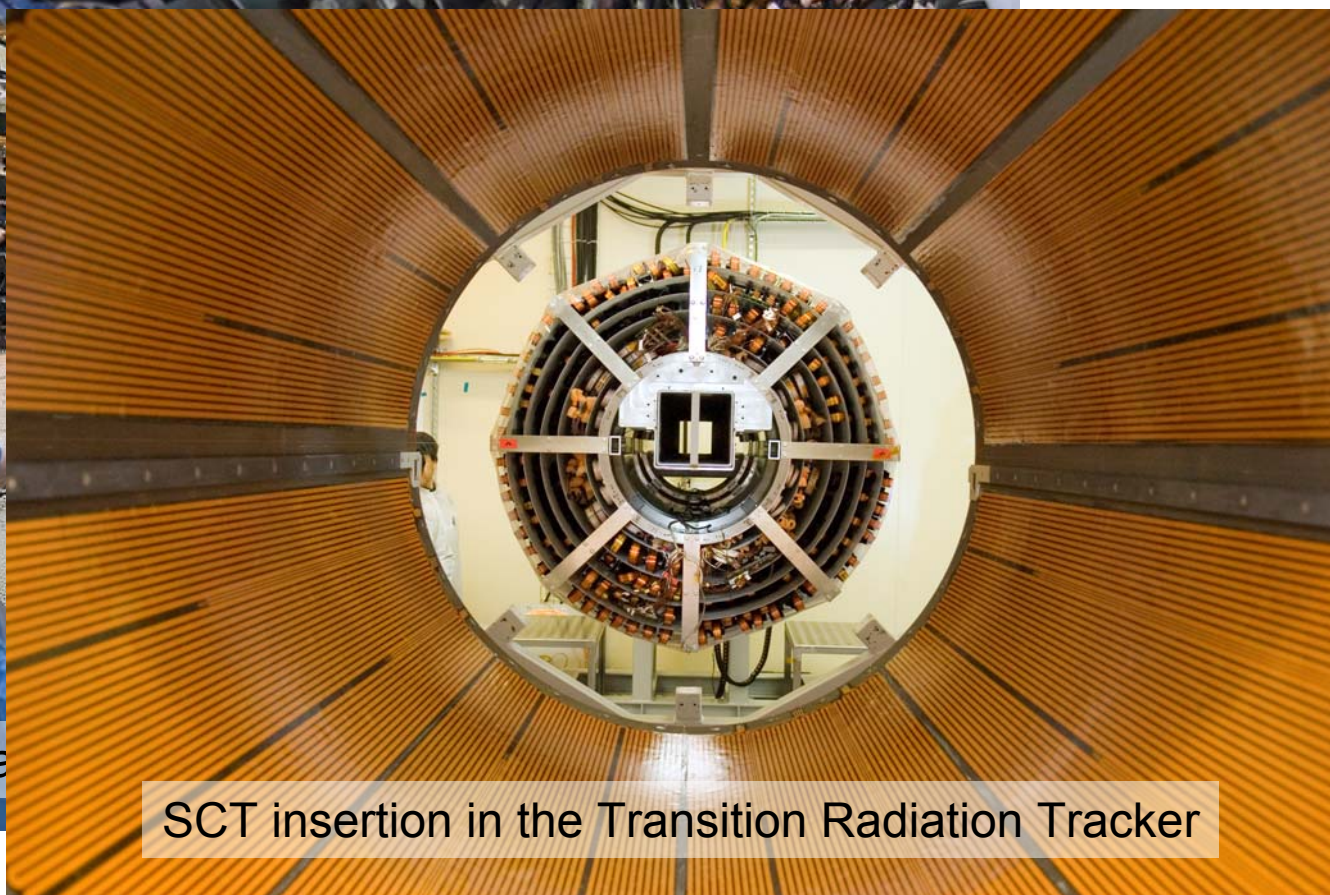
- ~26.7 m² of silicon
- ~3.0 x 10⁶ channels
- 1976 modules (4 types)
- Space point resolution:
 - $r\phi \sim 16$ mm
 - $R \sim 580$ mm
- Coverage: 1.1 to 1.4 $<|\eta| < 2.5$
- 9 disks



Atlas SCT integration



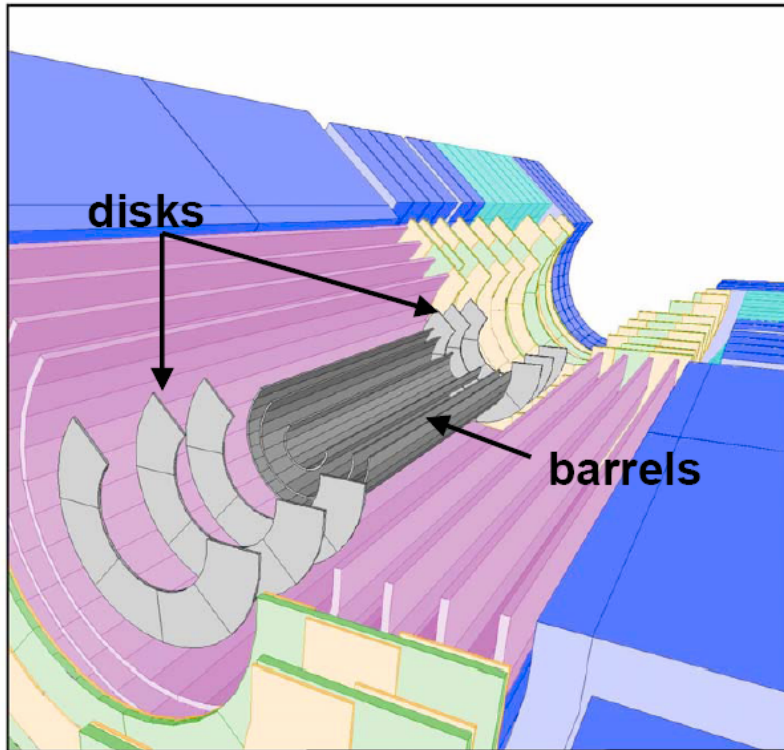
SCT layers integrat



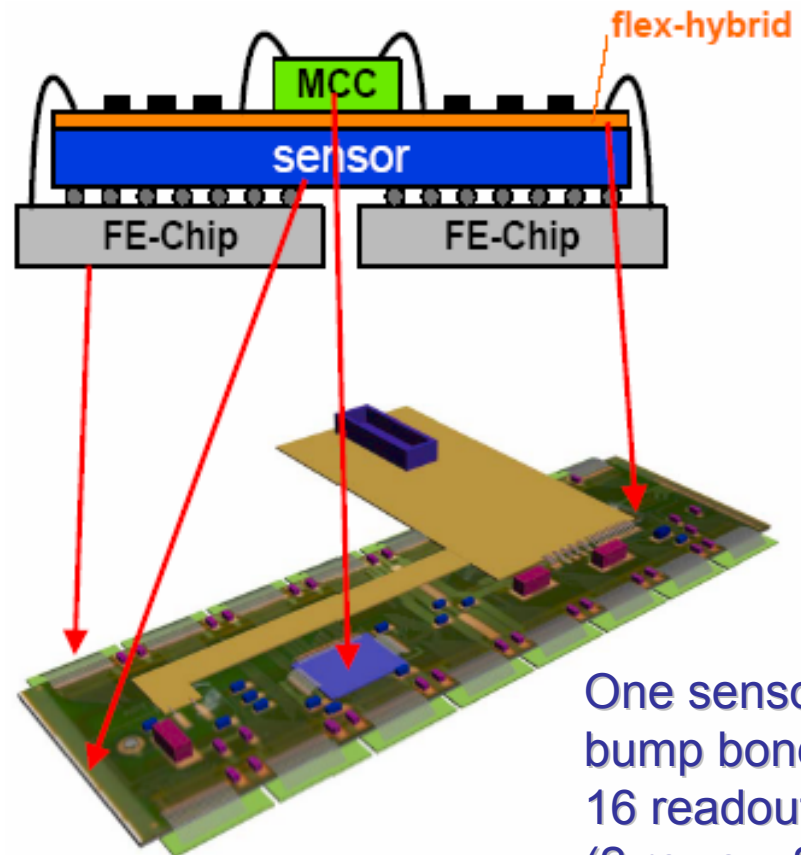
SCT insertion in the Transition Radiation Tracker

Silicon and TRT tracker integrated on February 17th, 2006

Atlas Pixel Detector



Technology: Hybrid pixels
1744 Readout modules
 8×10^7 pixel cells



Structure:

3 Barrel layers and 3 disks on each side
Innermost layer: $r=5$ cm
Length ~ 1.3 m (3 hits for $|\eta| < 2.5$)

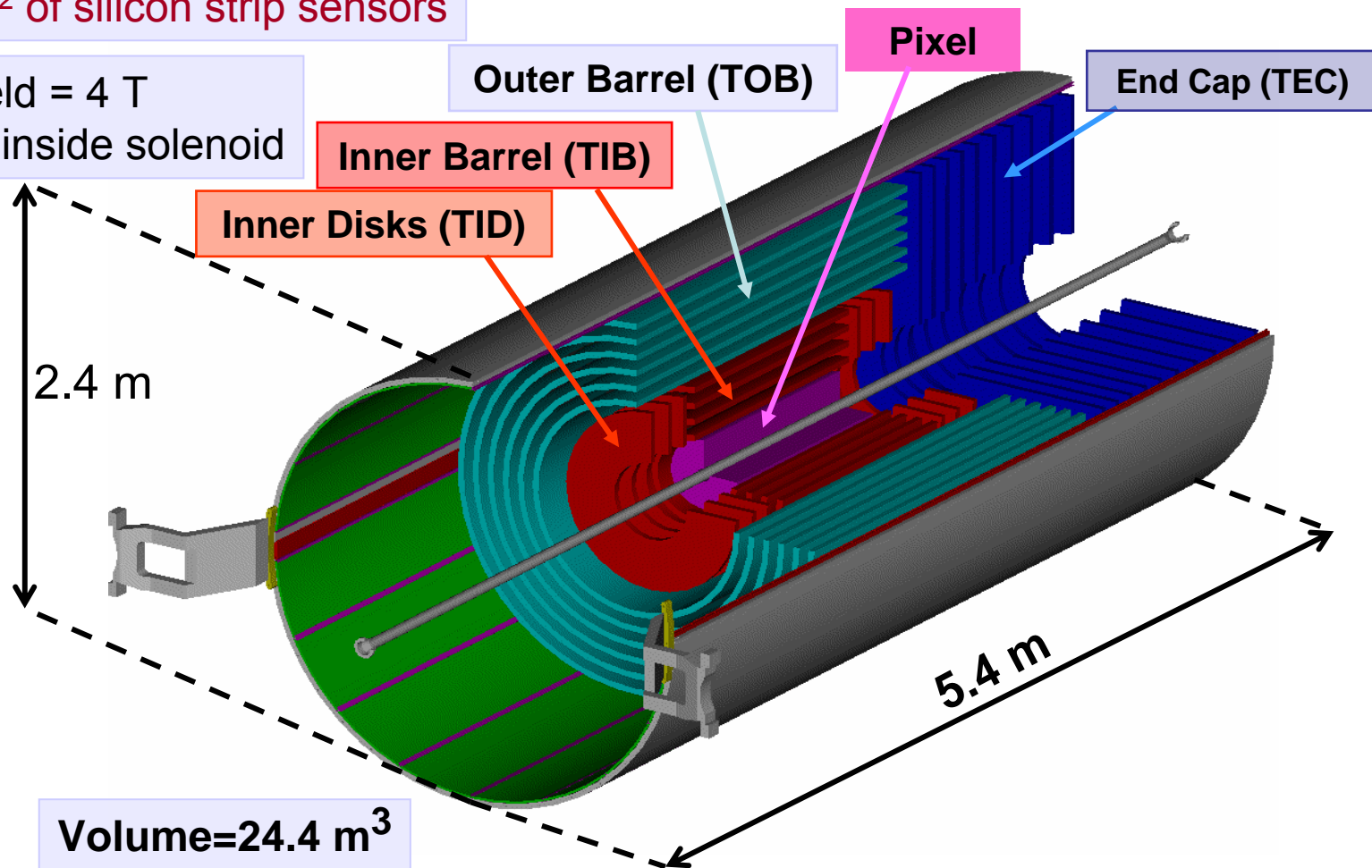
One sensor
bump bonded to
16 readout chips
(2 rows x 8 chips)

CMS Silicon Tracker

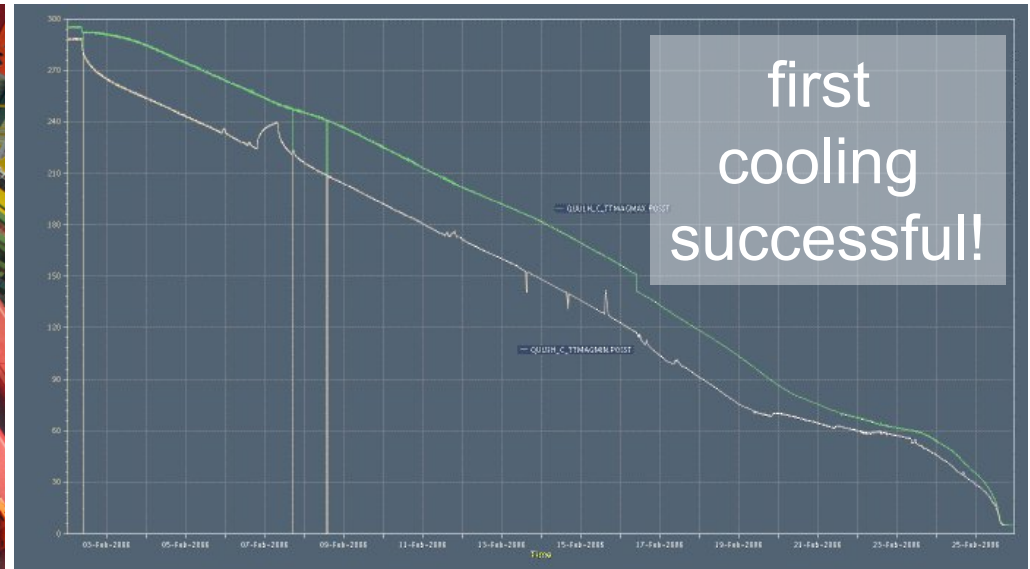
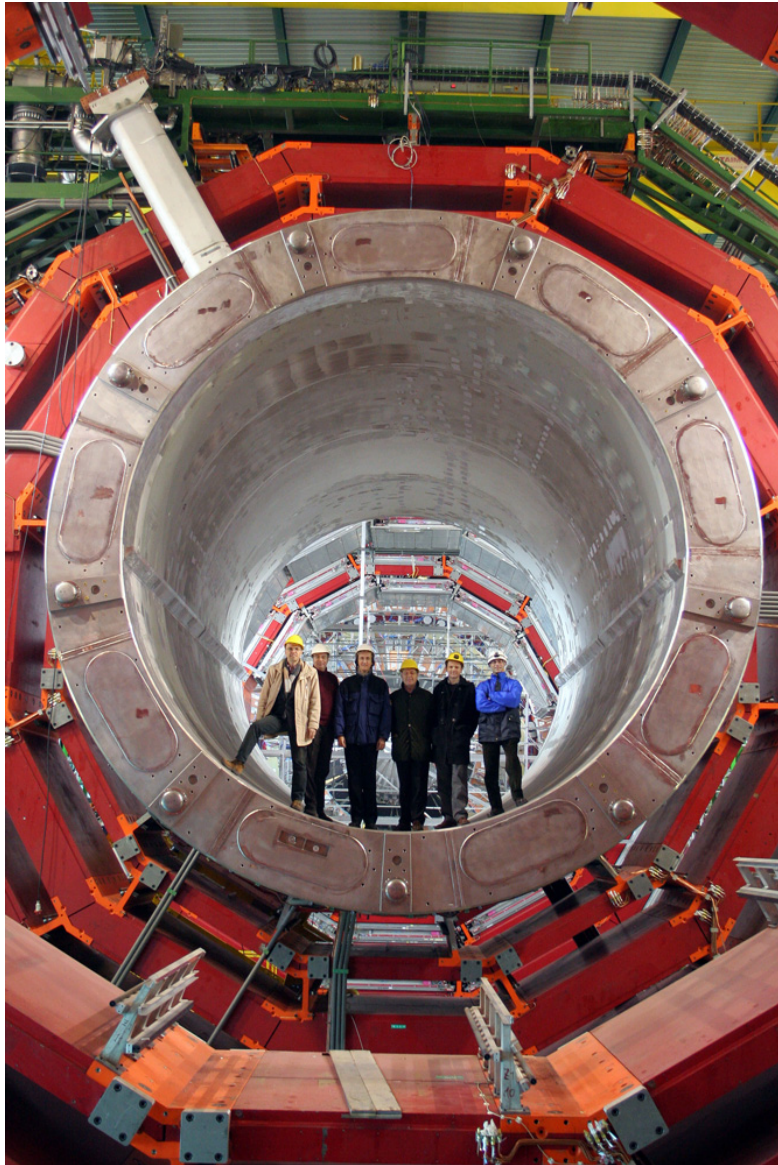


CDF & DØ ~ few m²
ATLAS ~ several *10m²
CMS ~ 210m² of silicon strip sensors

Solenoidal field = 4 T
Calorimeters inside solenoid



CMS Solenoid



← 23 days, 9 hours cooling down →

Conductor:

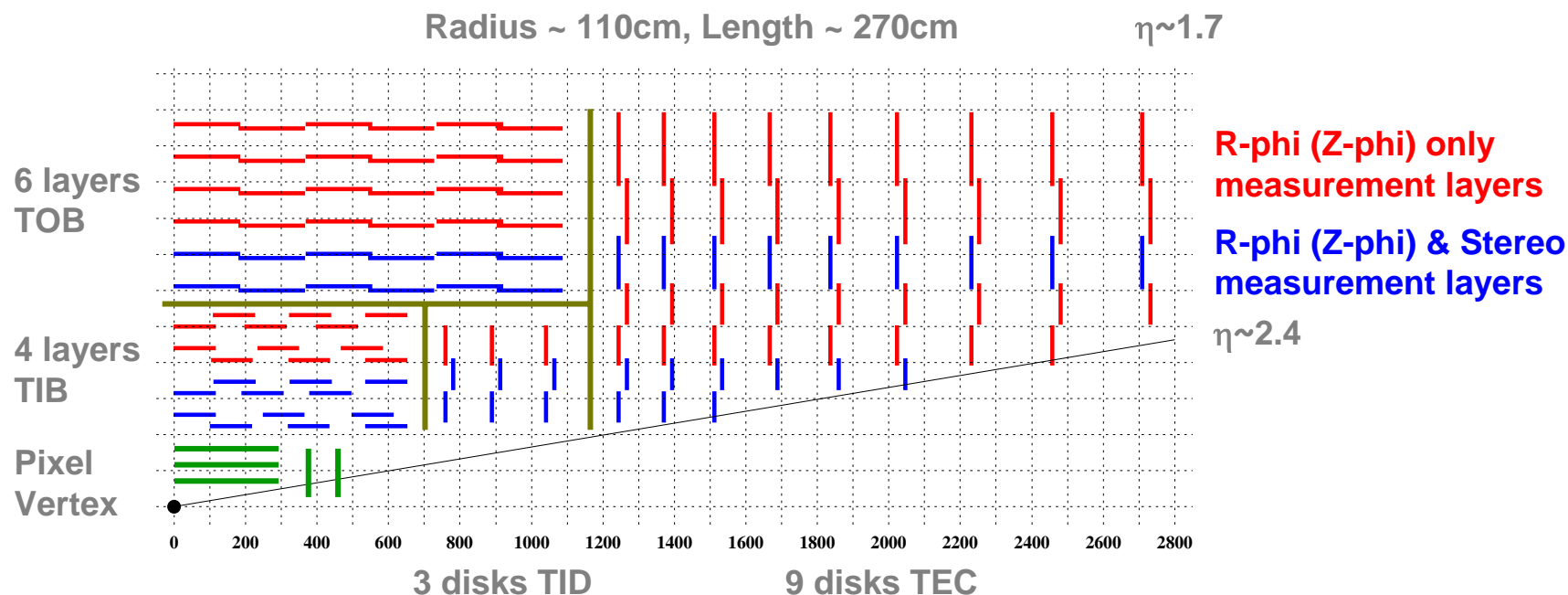
Superconductor cable (14.5 tonnes)
embedded in very pure aluminum (74 tonnes).

Structure:

Aluminum alloy (126 tonnes)
Insulation (9 tonnes),
Total mass of = 223.5 tonnes

B field = 4 T

Quarter of the CMS Tracker along the beam axis



- Rely on “few” measurement layers, each able to provide robust (clean) and precise coordinate determination:
 - 2 to 3 silicon pixel hits
 - 10 to 14 silicon strip hits

CMS SST: The components



Sensors:

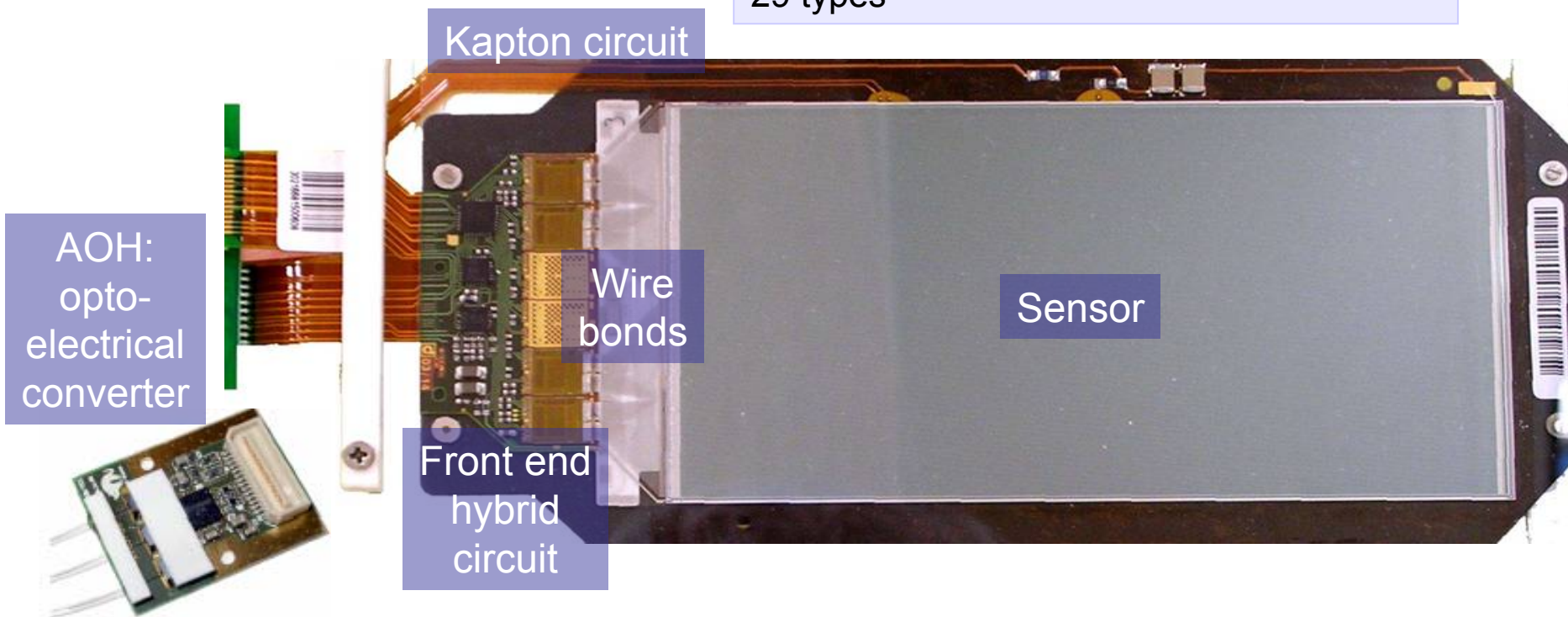
6,136 Thin + 18,192 Thick sensors
512 or 768 strips
Rectangular or trapezoidal sensors
9,648,128 strips = channels

Front-end chips:

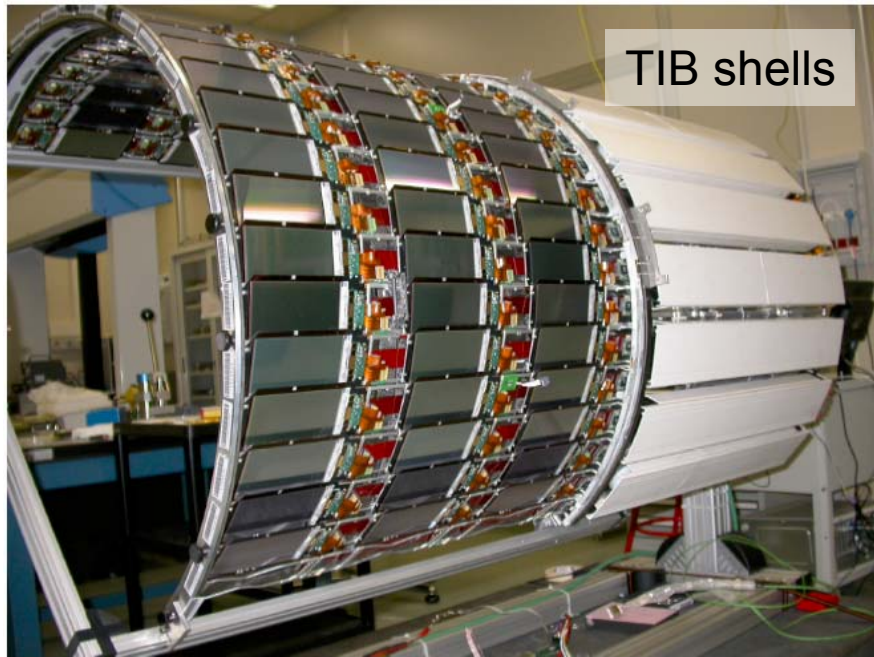
75,376 APV Chips (0,25 μm CMOS)
Sampling: Peak and deconvolution mode
128 ch, 4.8 μs pipeline depth
25 million wire bonds

Modules:

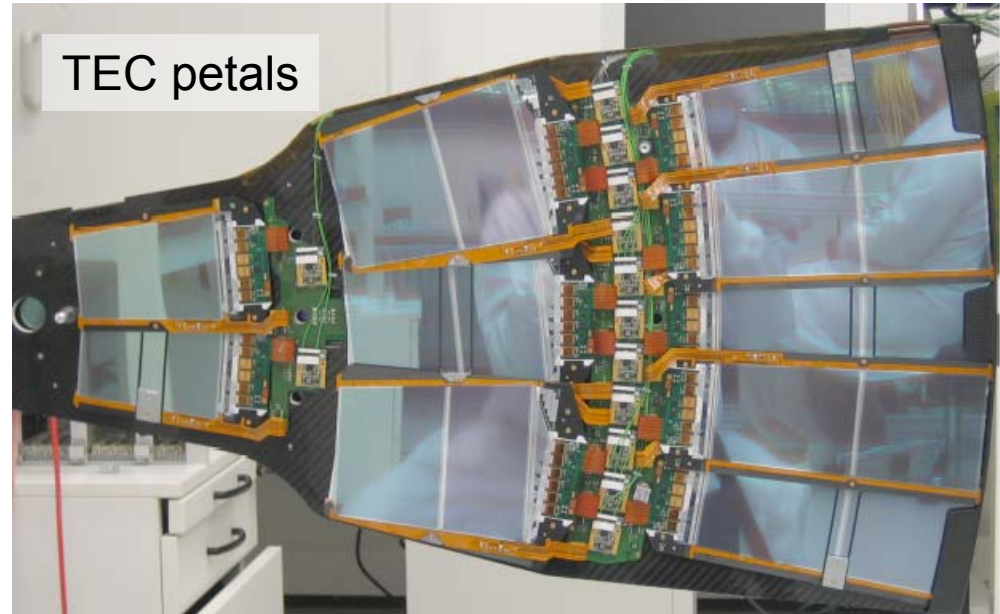
29 types



CMS SST: Integration



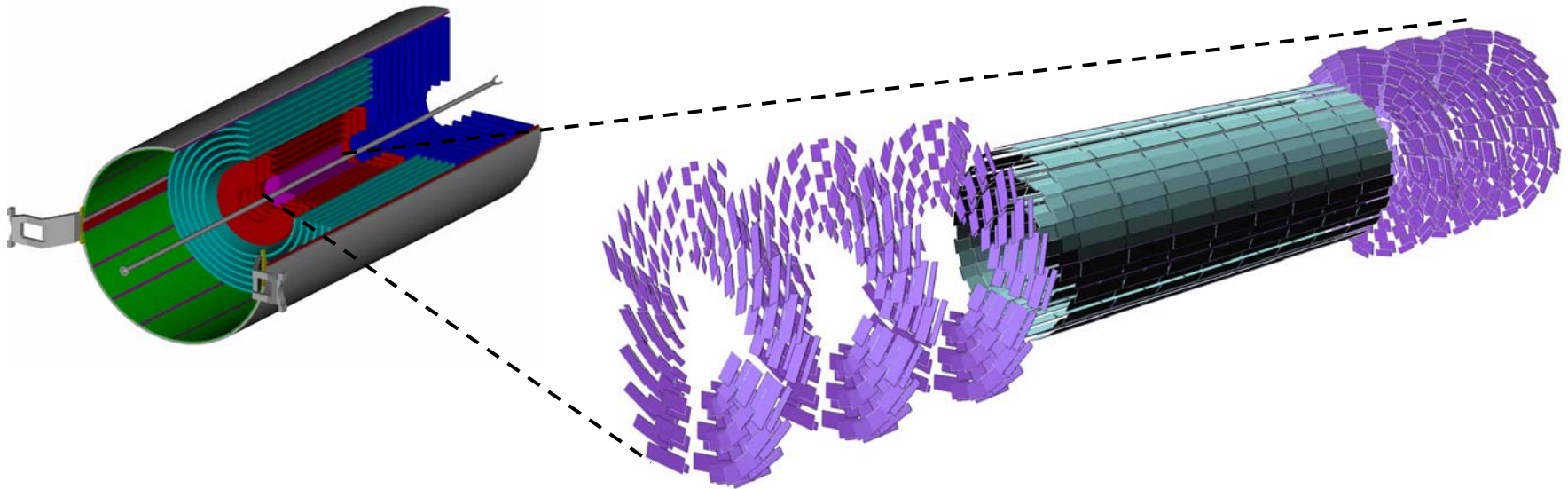
TIB shells



TEC petals



TOB rods

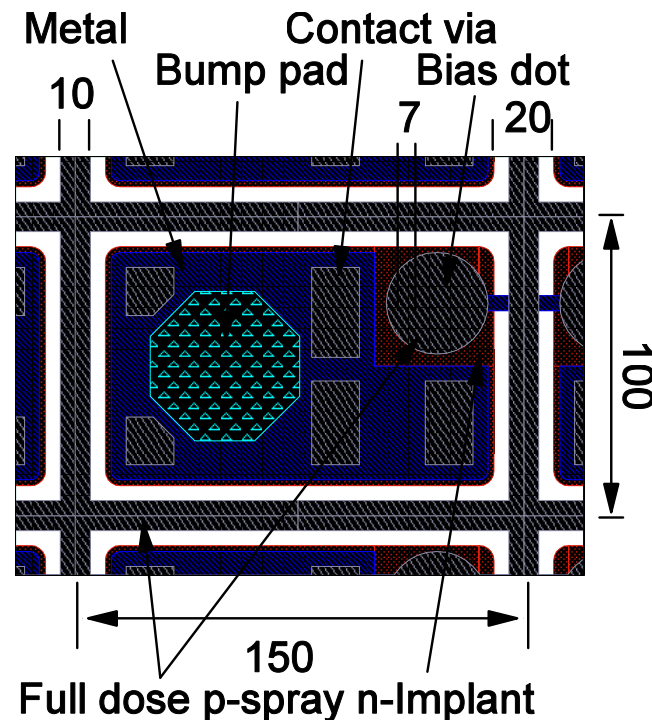
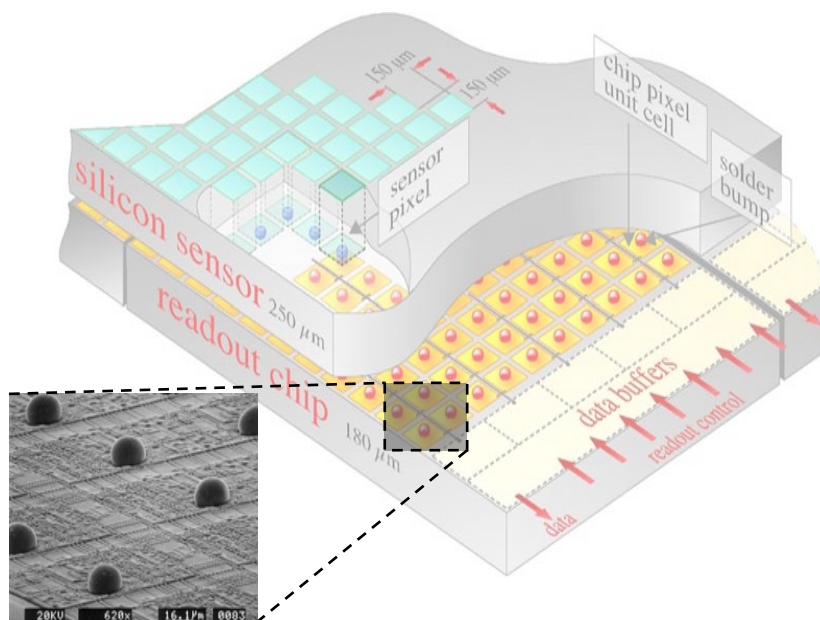


- Hybrid pixel technology
- 3-d tracking with about 66 million channels
- Barrel layers at radii = 4.3cm, 7.2cm and 11.0cm
- Pixel cell size = $100 \times 150 \mu\text{m}^2$
- 704 barrel modules, 96 barrel half modules, 672 endcap modules
- ~15,000 front-end chips and ~1m² of silicon

CMS Pixel sensors

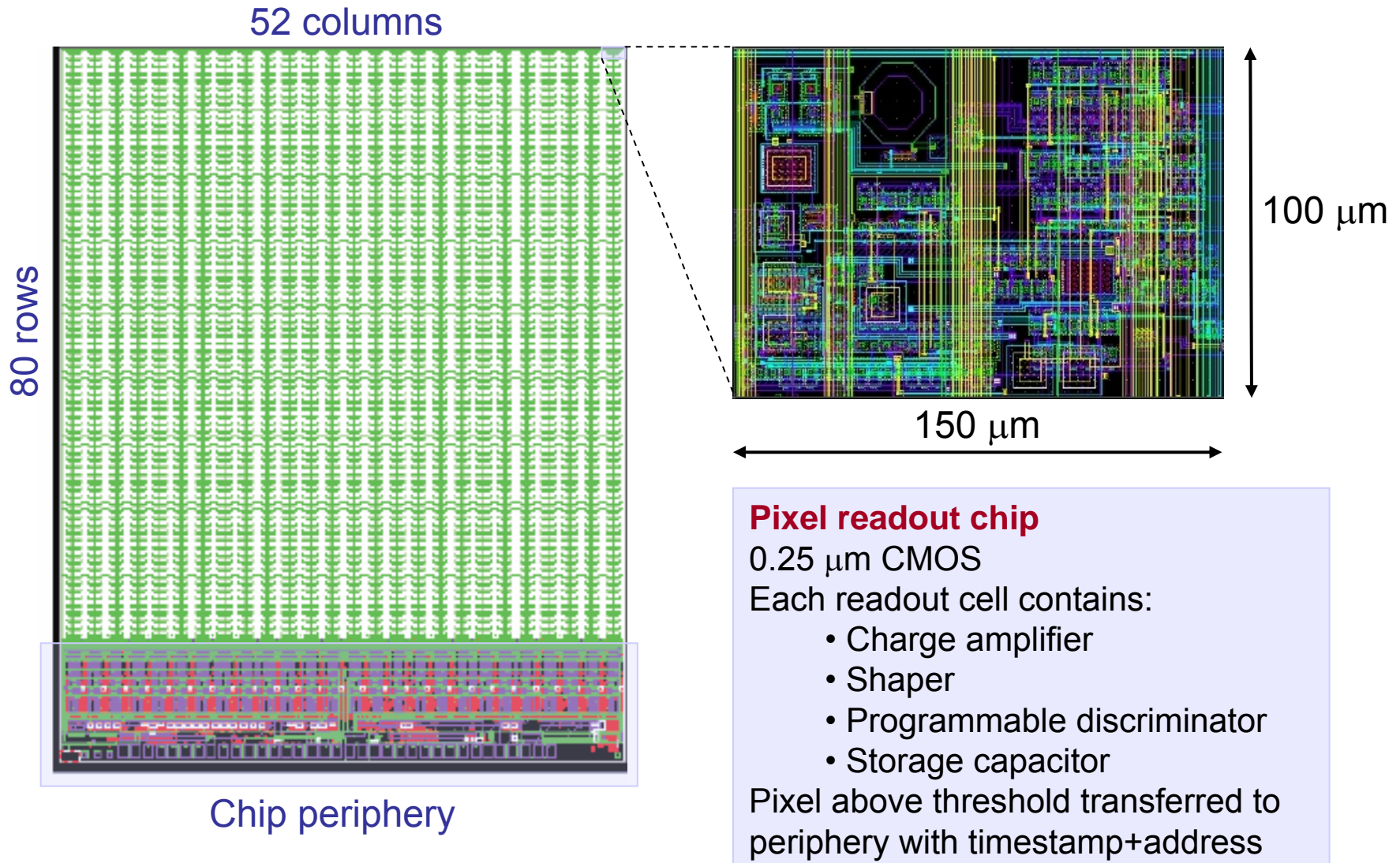
Hybrid pixel detector

Each pixel cell is bump-bonded to its own front end circuit

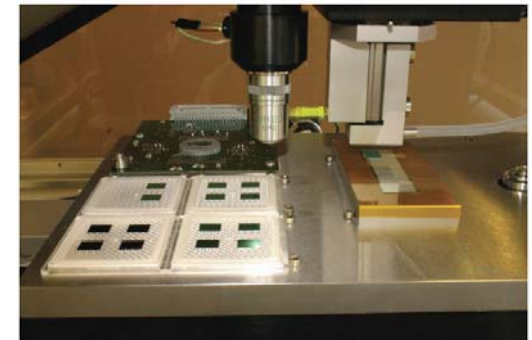
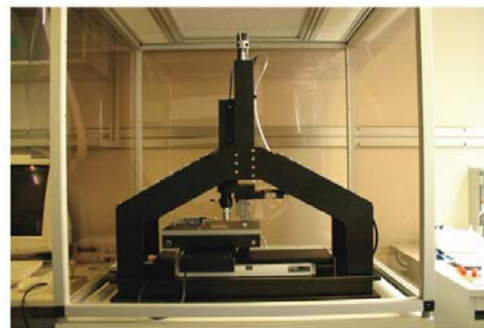
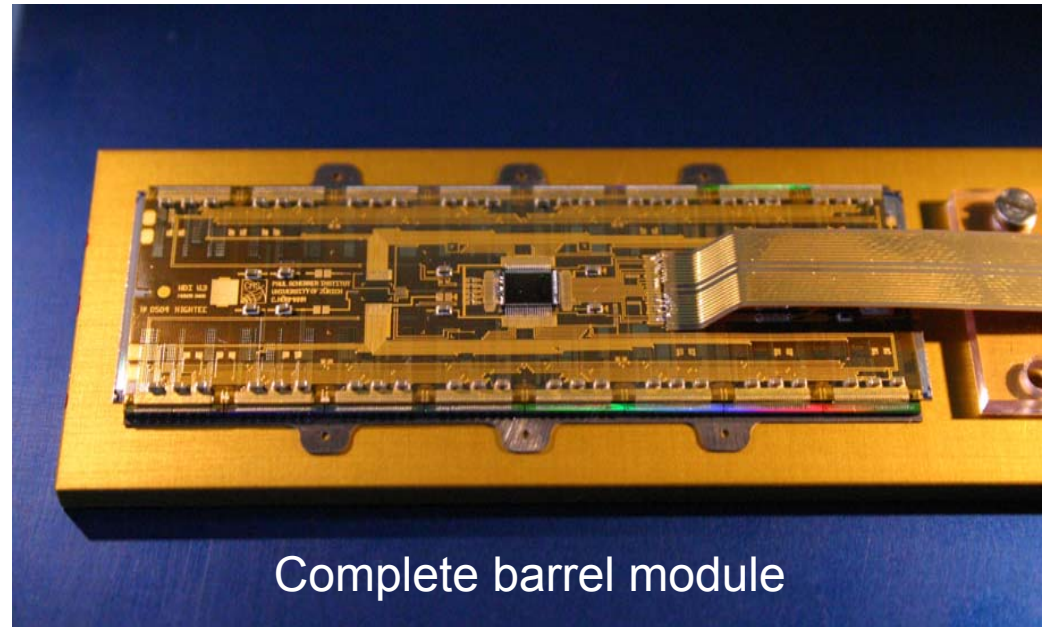
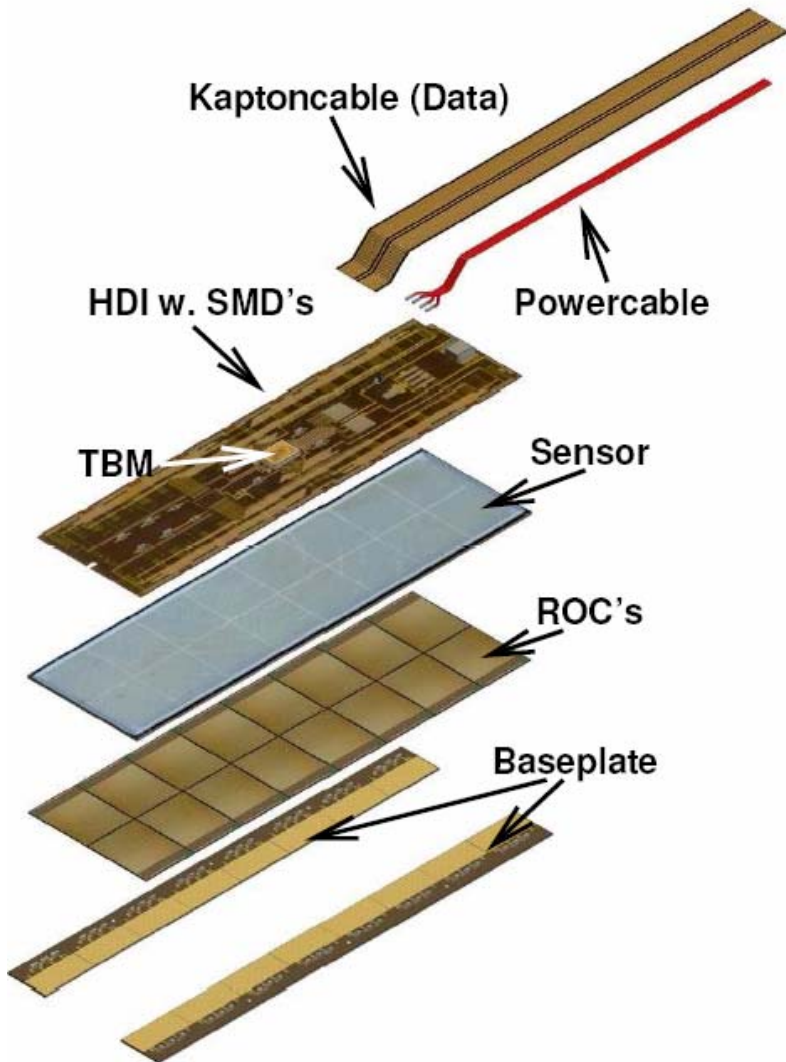


- *n-in-n* type with moderated p-spray isolation
- biasing grid and punch through structures (keeps unconnected pixels at ground potential, I-V tests possible)
- 285 μm thick <111> DOFZ wafer

CMS Pixel readout chip



CMS Pixel modules

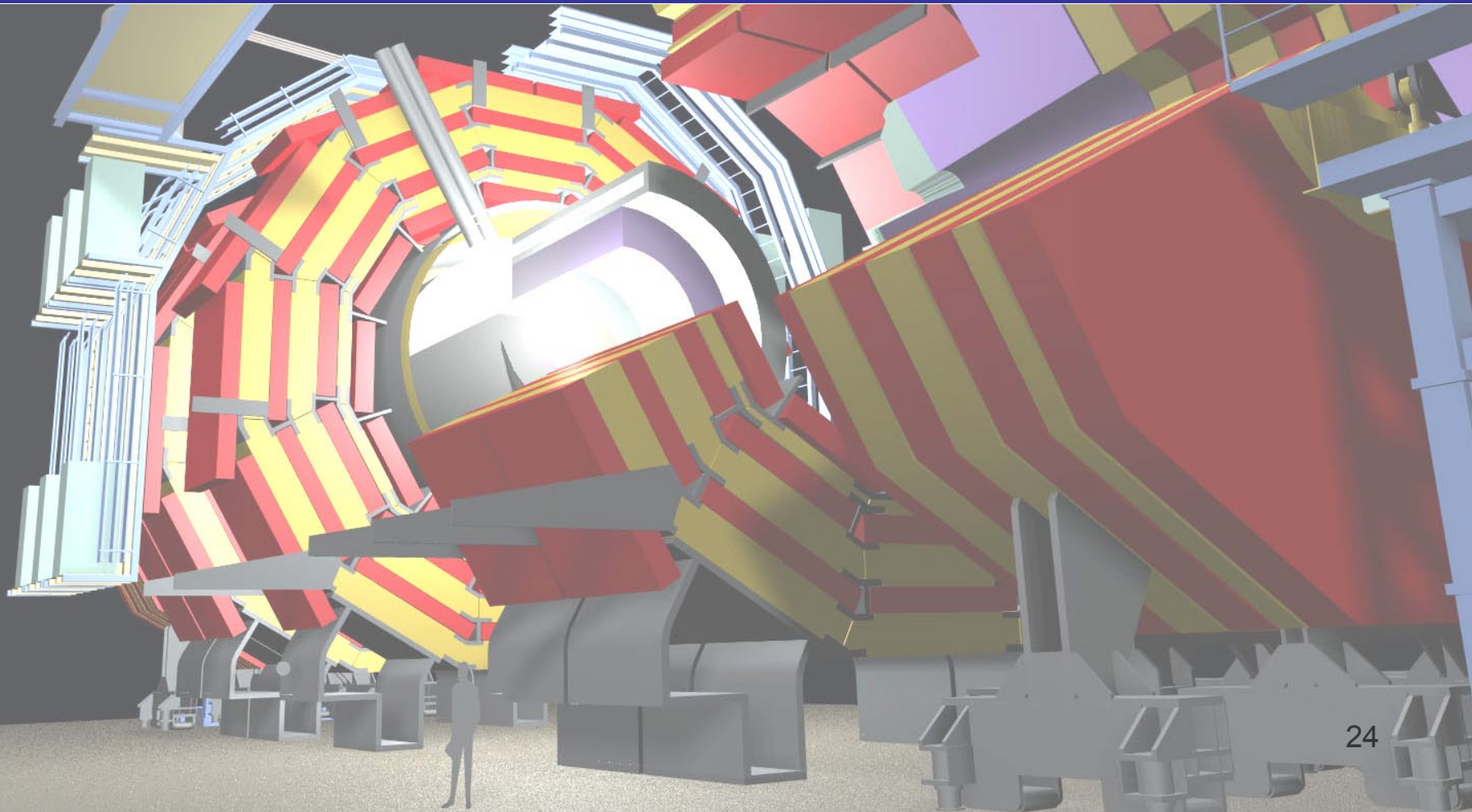


Automatic bump bonding in-house at PSI



- **Priorities for 2006:**
 - Complete integration and commissioning of the Tracker at CERN
 - Magnet test and cosmic challenge: CMS slice test with cosmics
 - 25% System test
- **HW Status:**
 - TIB+/TID+ integration in Italy in very good shape.
 - TEC+ integration in Aachen started (first sector of 18 petals completed)
 - TOB integration planned to start at CERN (week 9). TOB module construction completed at FNAL.
 - Pixels: start barrel module production May 06. Mechanical support structures for 2007 pilot run ready by end 06.
- **SW plans:**
 - Software for magnet test fully commissioned by April 06
 - Software for 25% system test fully commissioned by June 06

Performance degradation after irradiation

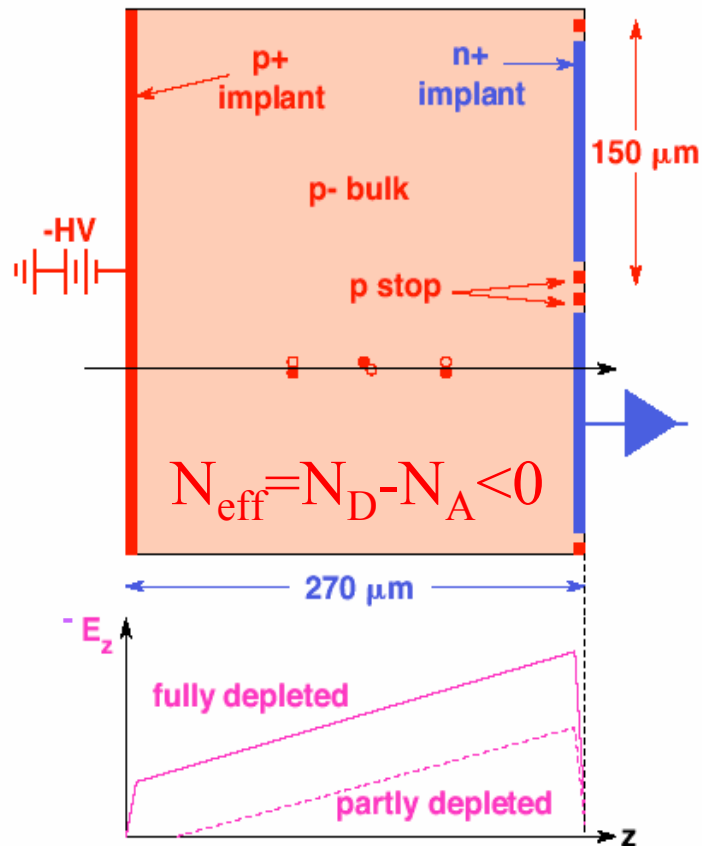




- “Assembled and installed detector” does not mean “ready for physics”!
- Detector commissioning and calibration software development is a very delicate phase where detectors experts and sw developers must collaborate and share know-how.
- Calibration of a silicon detector involves e.g.:
 - Pedestals, tune thresholds, spot noisy or dead channels
 - Charge collection efficiency and trapping
 - Lorentz angle, alignment etc.
- The physical properties of a silicon detector will change under heavy irradiation. Calibrations must be kept up-to-date.
- A “case study”: CMS pixels (similar case for LHC strip detectors but lower fluence, no oxygenation)

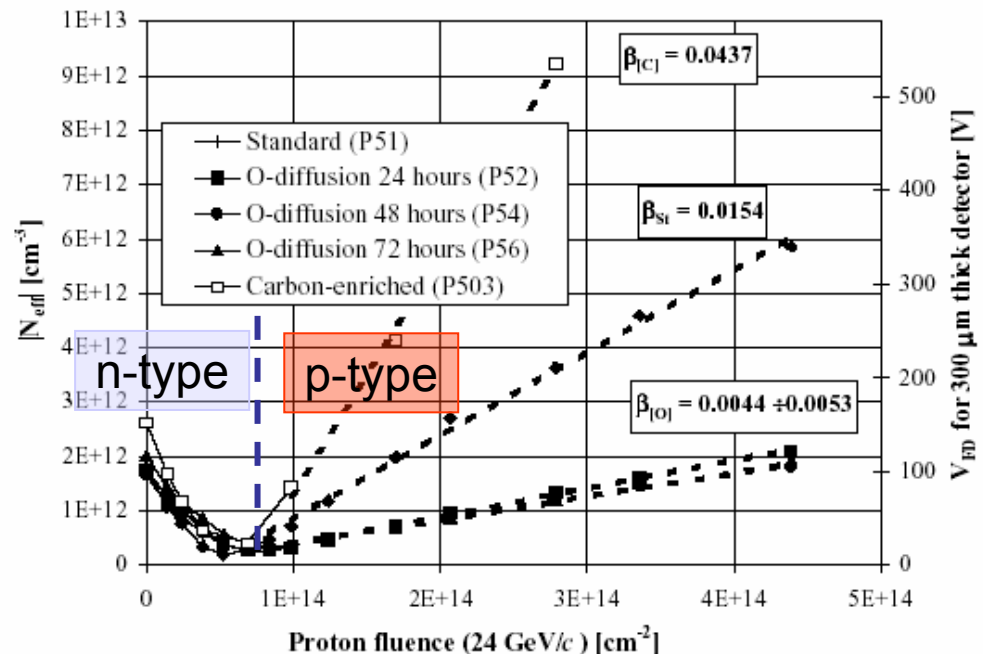
Type inversion

after type inversion



- After irradiation the sensor bulk becomes more acceptor-like
- The space charge density is constant and negative across the sensor thickness
- The p-n junction moves to the pixel implants side
- Sensors may be operated in “partial depletion”

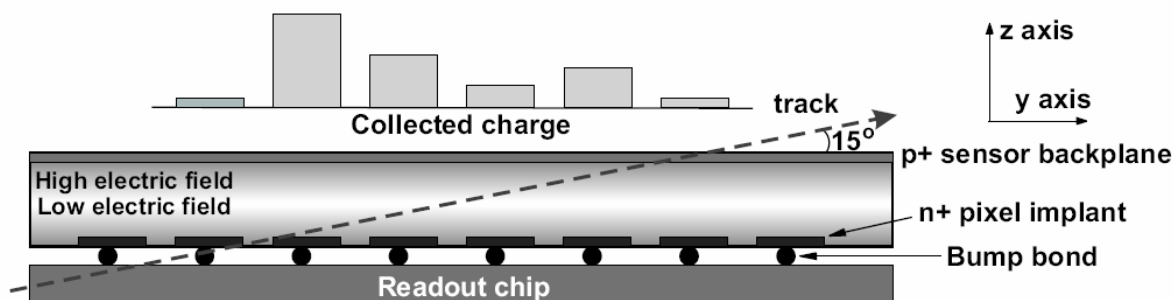
Based on C-V measurements!
...is all this really true?



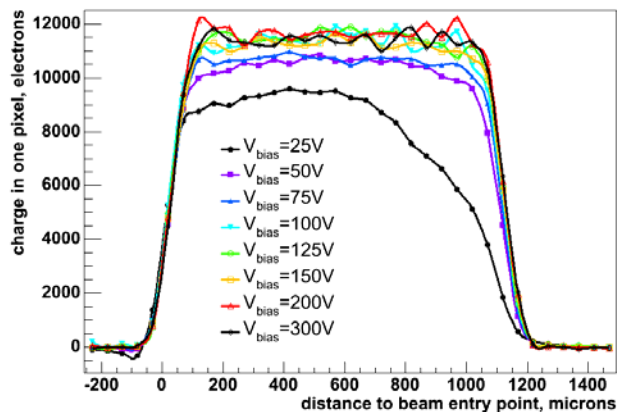
Charge collection measurements



Charge collection was measured using cluster profiles in a row of pixels illuminated by a 15° beam and no magnetic field

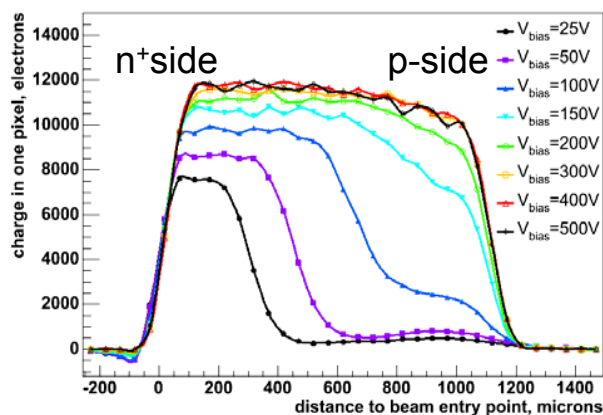


$$\Phi_{eq} = 5 \times 10^{13} \text{ n/cm}^2$$



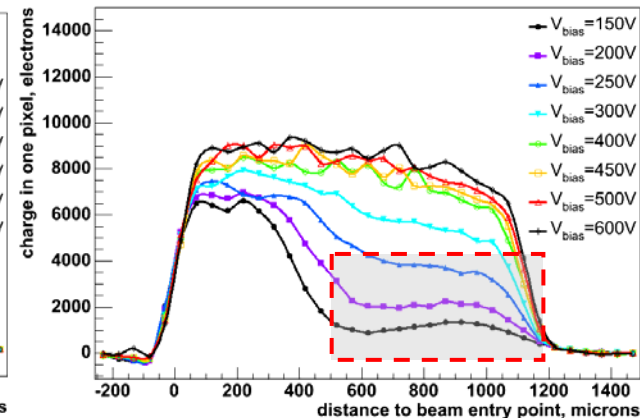
1/2 year LHC low luminosity

$$\Phi_{eq} = 2 \times 10^{14} \text{ n/cm}^2$$



2 years LHC low luminosity

$$\Phi_{eq} = 6 \times 10^{14} \text{ n/cm}^2$$



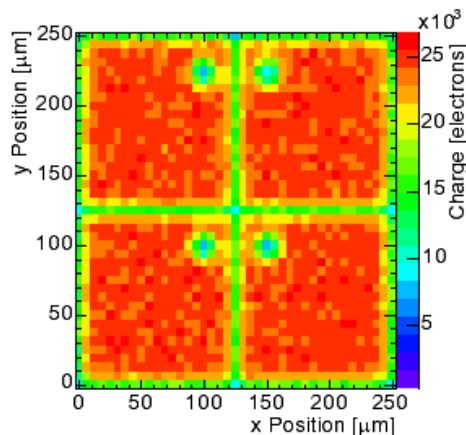
2 years LHC high luminosity

AGEING

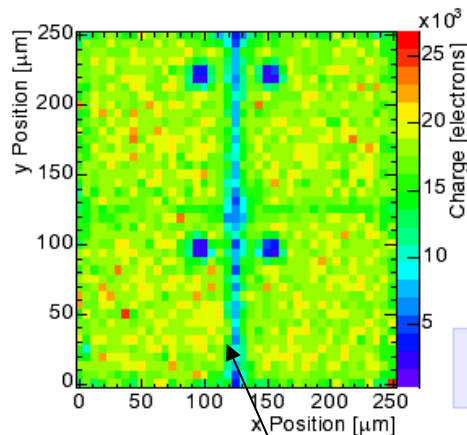
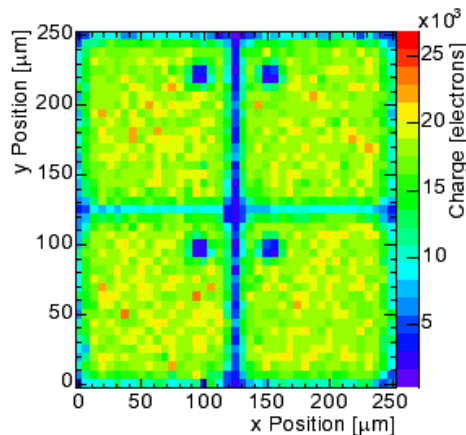
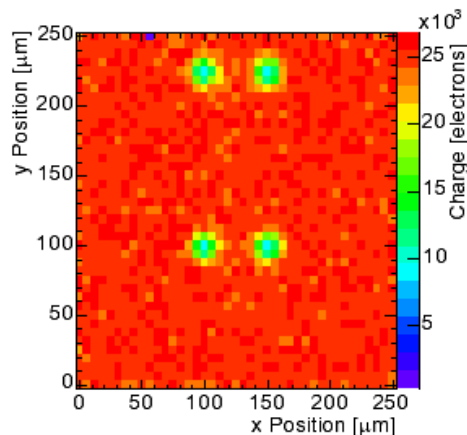
Hit detection efficiency



hit pixel



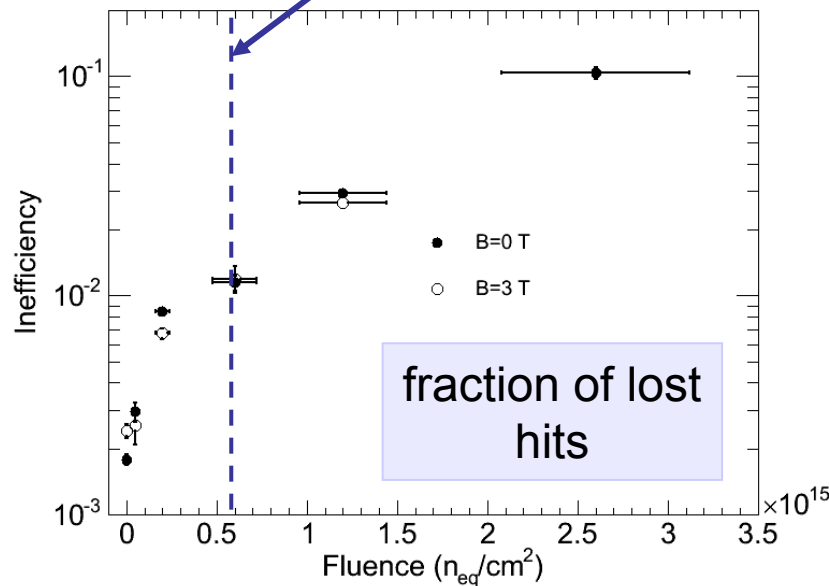
cluster sum



Charge losses below metal biasing grid

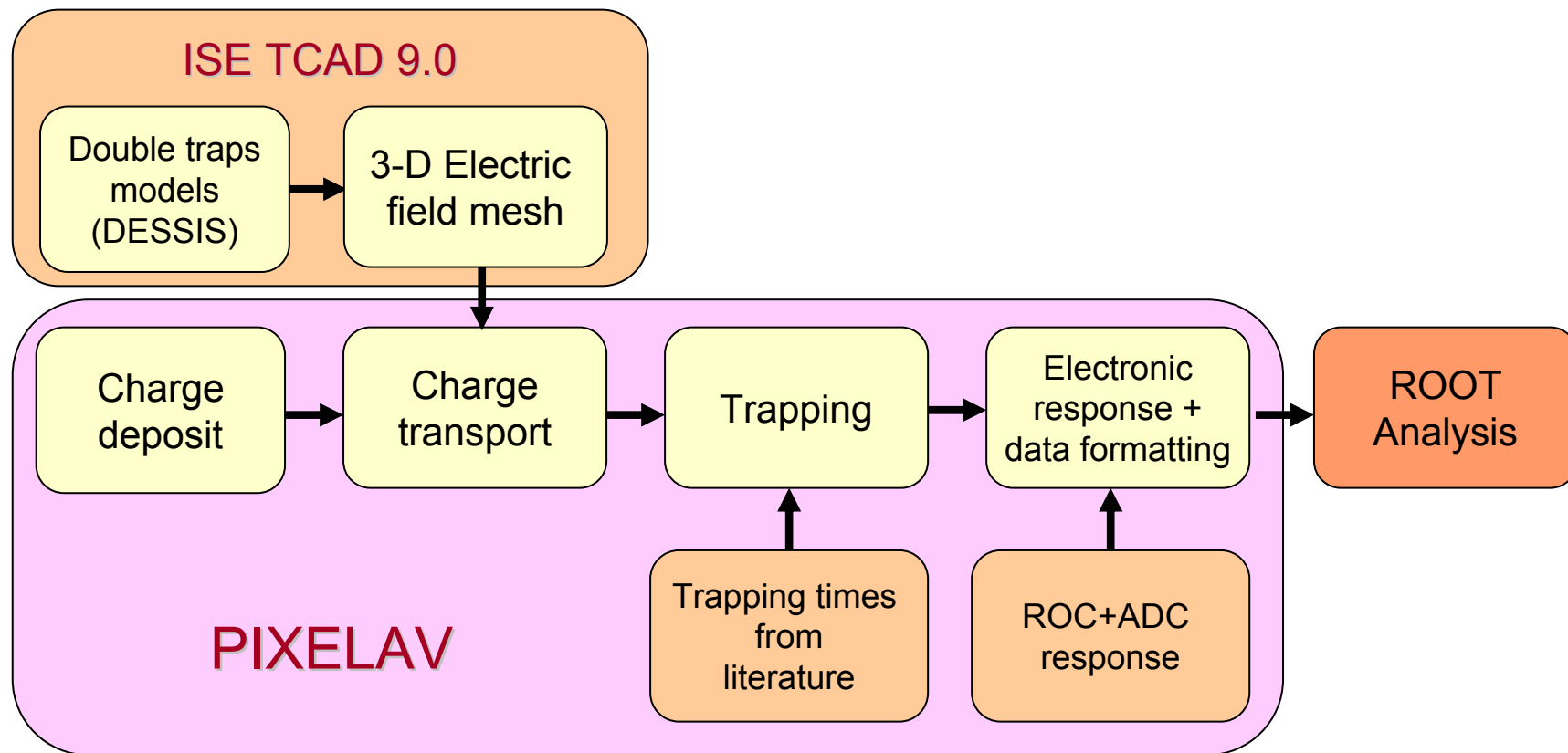
unirradiated

specified radiation hardness



$\Phi = 6 \times 10^{14} \text{ n/cm}^2$

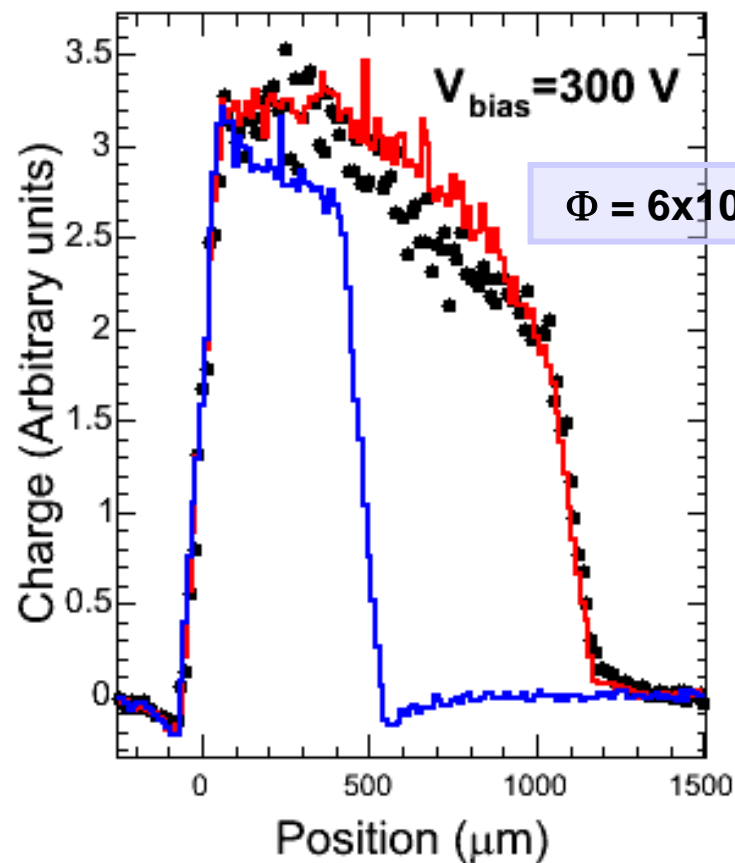
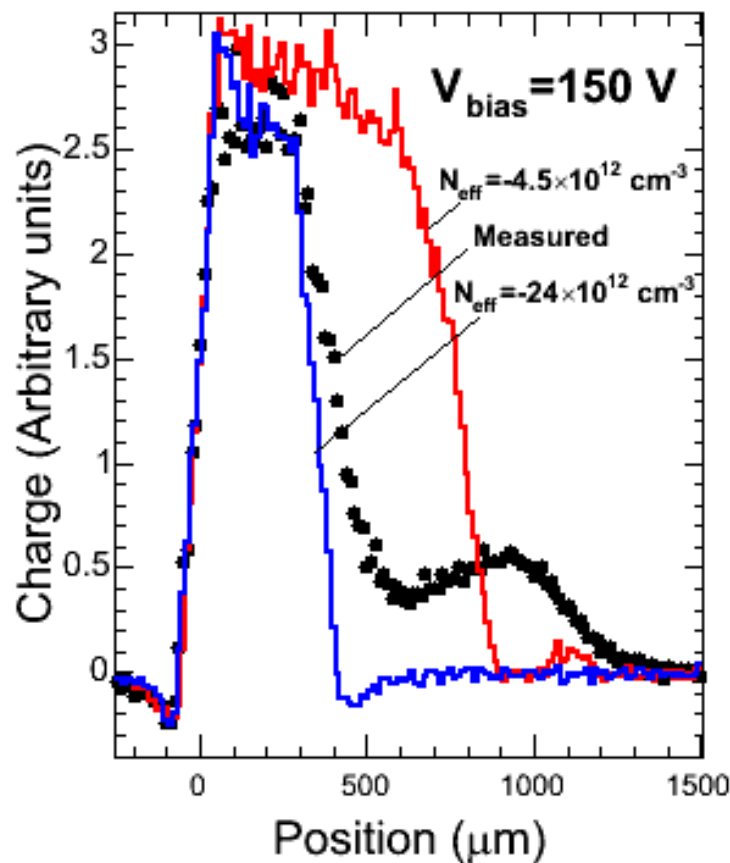
Detector simulation



M.Swartz, *Nucl.Instr. Meth. A*511, 88 (2003);

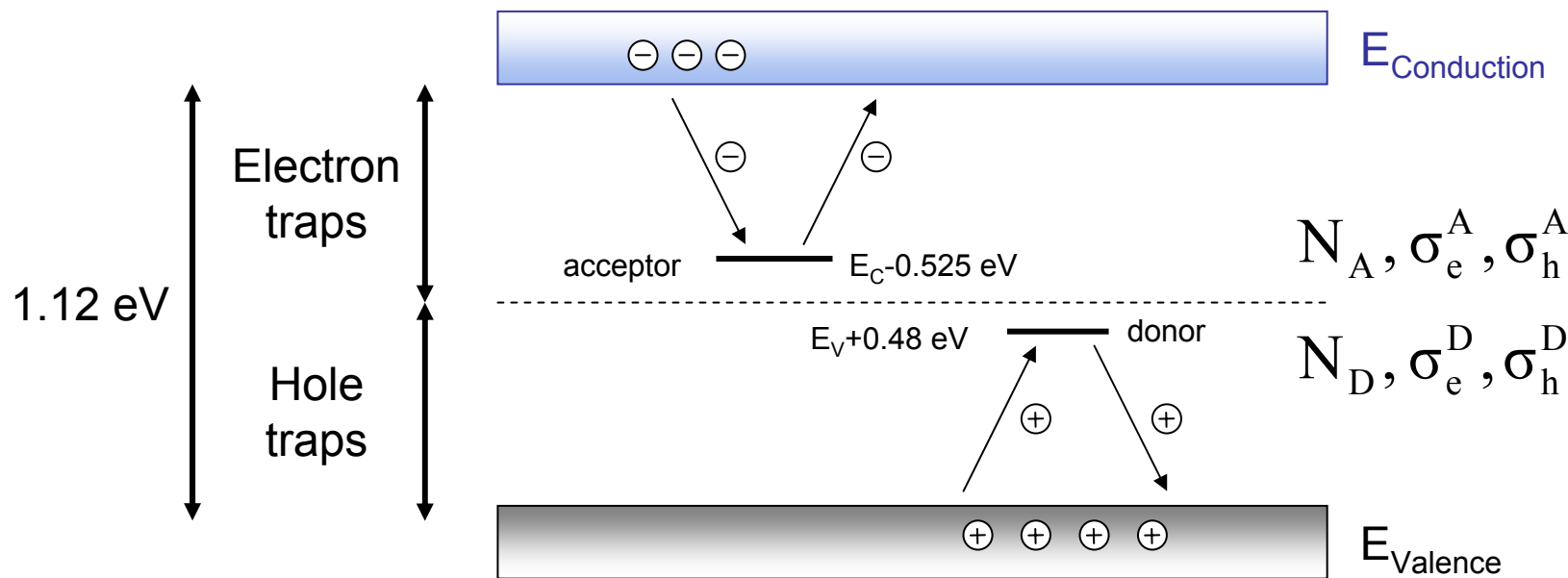
V.Chiochia, M.Swartz et al., *IEEE Trans.Nucl.Sci.* 52-4, p.1067 (2005).

Models with constant N_{eff}



A model based on a type-inverted device with **constant space charge density** across the bulk **does not describe** the measured charge collection profiles

Two-traps effective models

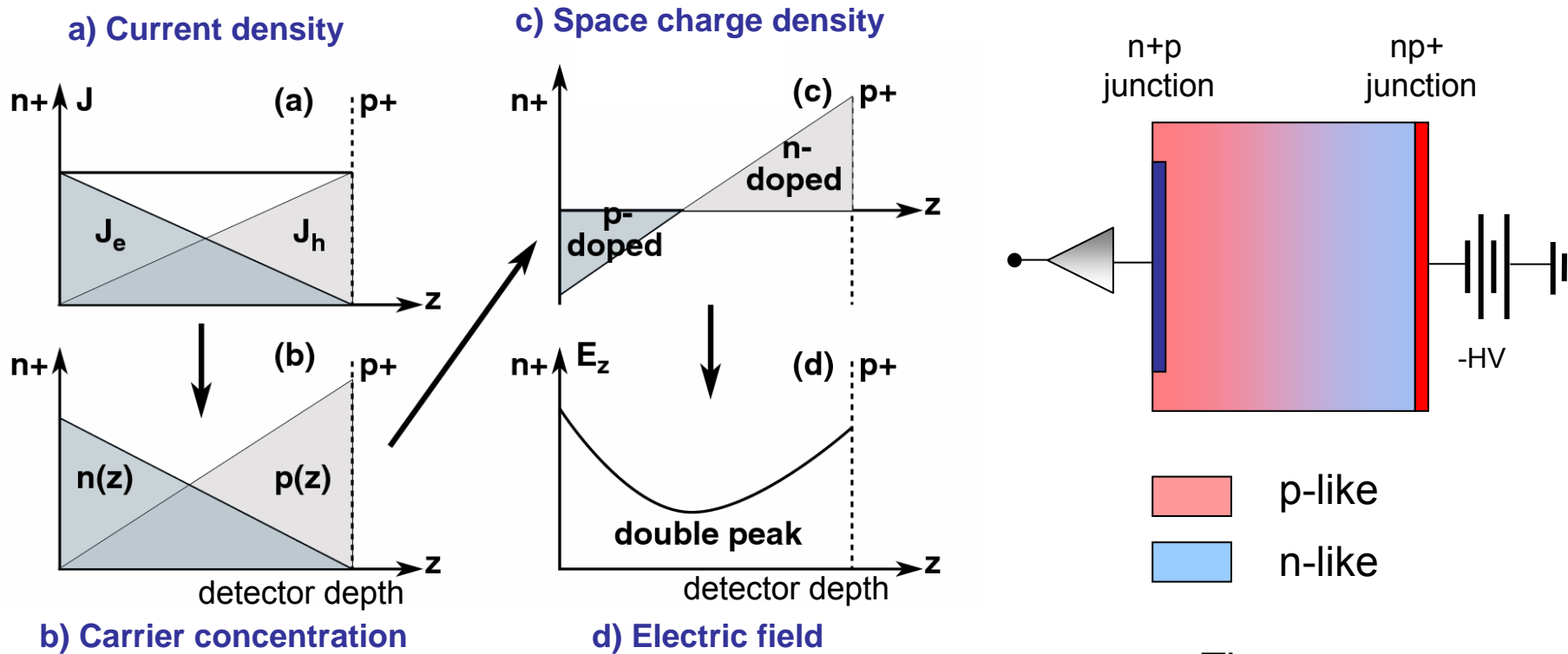


Model parameters
(Shockley-Read-Hall statistics):

$$\begin{cases} E_{A/D} = \text{trap energy level} \\ N_{A/D} = \text{trap densities} \\ \sigma_{e/h} = \text{trapping cross sections} \end{cases}$$

fixed
extracted from fit
extracted from fit

The double peak electric field



V.Eremin *et al.*, NIM A 476 (2002) p476, NIM A 476 (2002) p537

There are
P-N junctions at both
 sides of the detector

- Idea: extract model parameters from a fit to the data
- The two-trap model is constrained by:
 1. Comparison with the measured charge collection profiles
 2. Signal trapping rates varied within uncertainties

$$Q_{e,h}(t) = Q_{0e,h} \exp\left(-\frac{1}{\tau_{e/h}} t\right)$$

$$\Gamma_e = 1/\tau_e = \beta_e \Phi_{eq} \cong v_e \sigma_e^A N_A$$

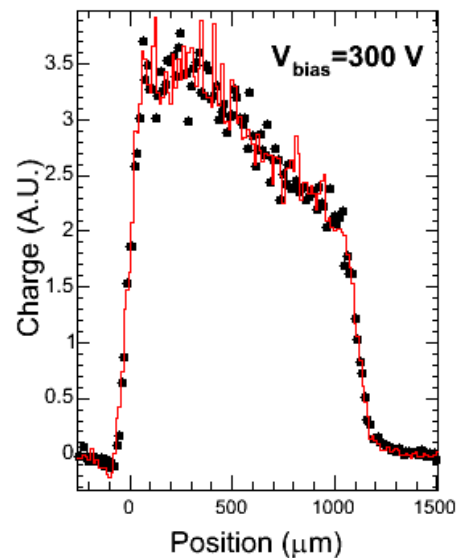
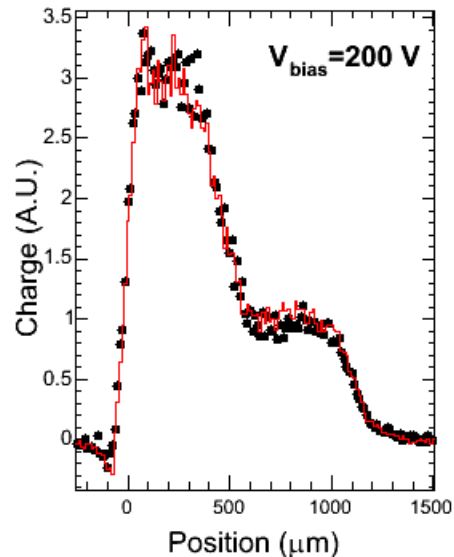
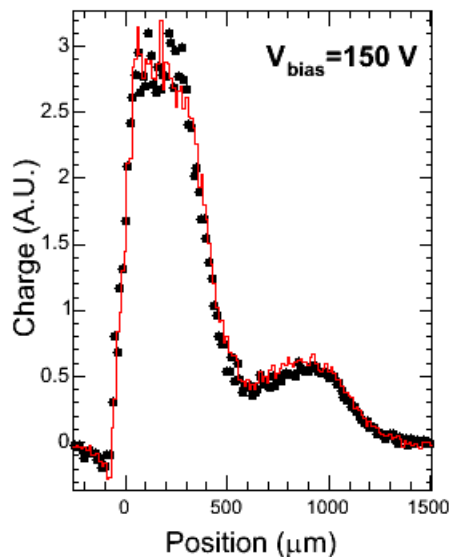
$$\Gamma_h = 1/\tau_h = \beta_h \Phi_{eq} \cong v_h \sigma_h^D N_D$$

3. Measured dark current

$$I = \sum_{j=D,A} \frac{v_h v_e \sigma_h^j \sigma_e^j N_D (np - n_i^2)}{v_e \sigma_e^j (n + n_i e^{E_j/kT}) + v_h \sigma_h^j (p + n_i e^{-E_j/kT})}$$

Typical fit iteration: (8-12h TCAD) + (8-16h PIXELAV)xV_{bias} + ROOT analysis

Fit results



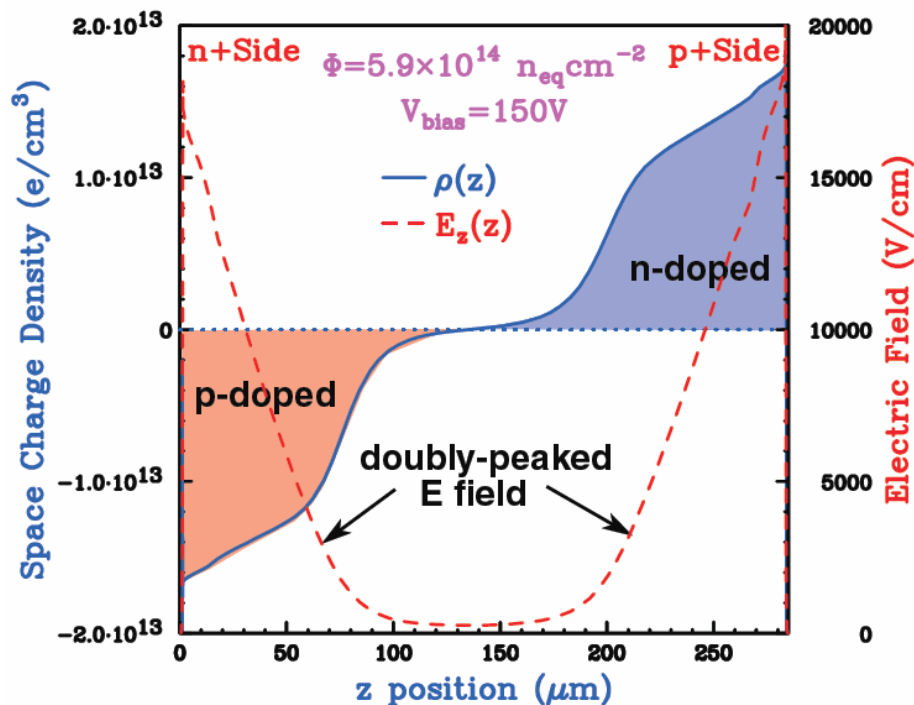
$$\Phi_1 = 6 \times 10^{14} \text{ n/cm}^2$$

$$N_A/N_D = 0.40$$

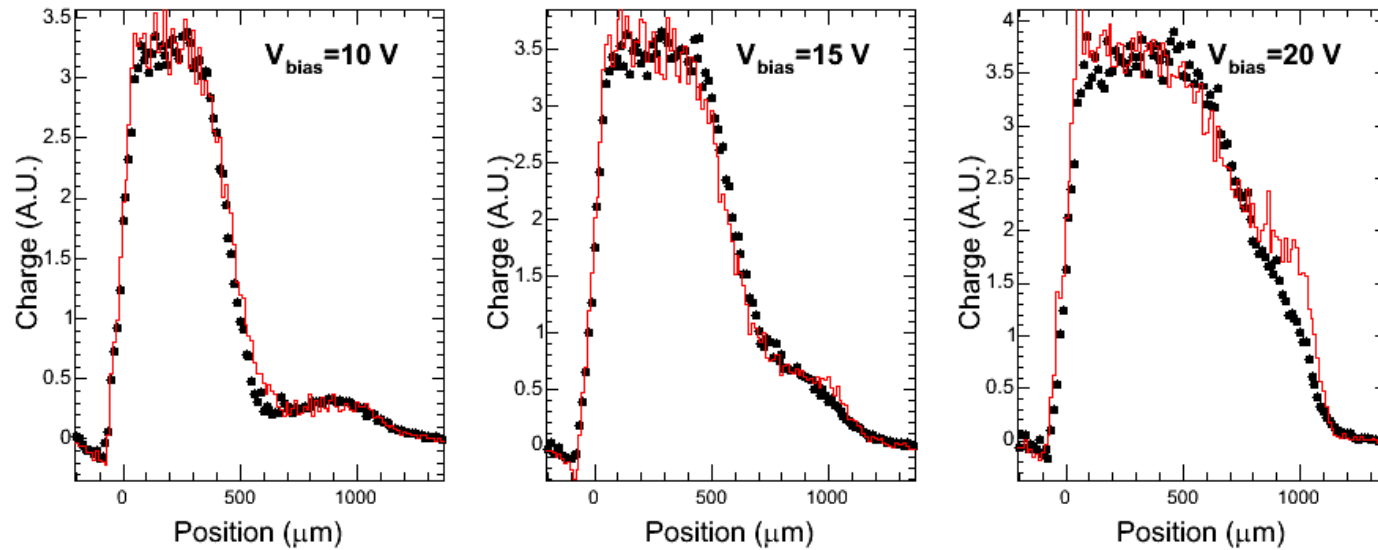
$$\sigma_h/\sigma_e = 0.25$$

● Data
— Simulation

Electric field and space charge density profiles

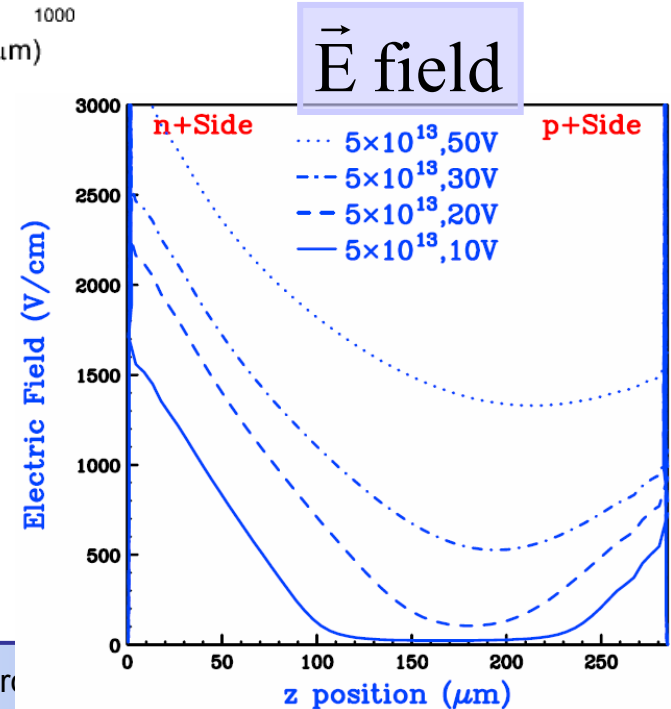


Scaling to lower fluences

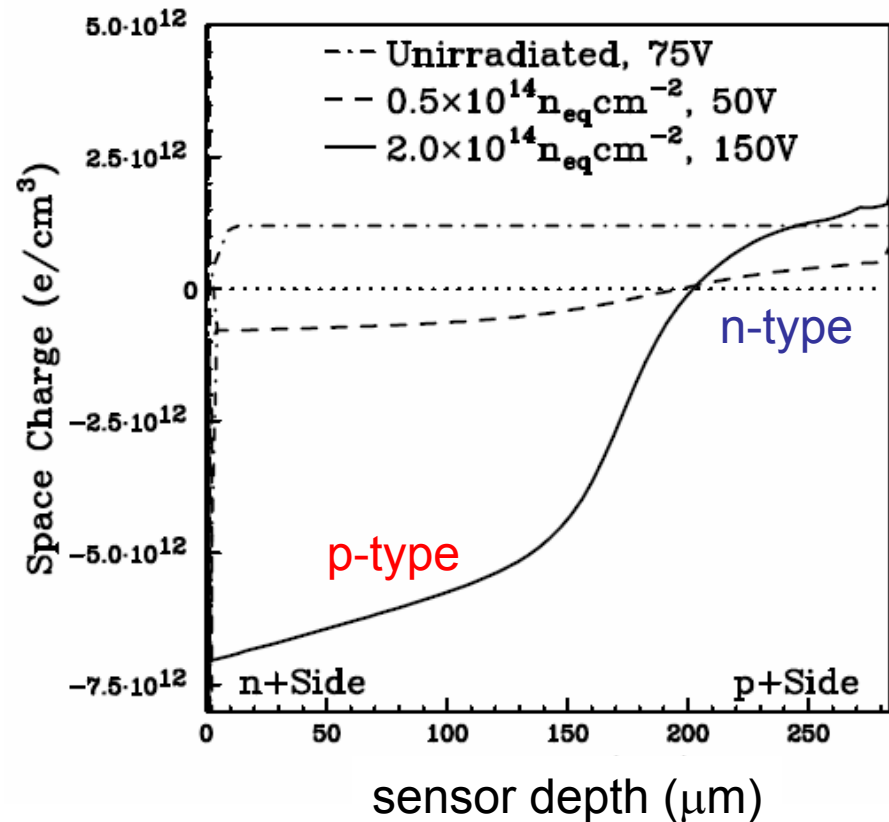


$\Phi_3 = 0.5 \times 10^{14} \text{ n/cm}^2$
 $N_A/N_D = 0.75$
 $\sigma_h^A/\sigma_e^A = 0.25$
 $\sigma_h^D/\sigma_e^D = 1.00$

- Near the ‘**type-inversion**’ point: the double peak structure is still visible in the data!
- Profiles are not described by thermodynamically ionized acceptors alone
- At these low bias voltages the drift times are comparable to the preamp shaping time (simulation may be not 100% reliable)



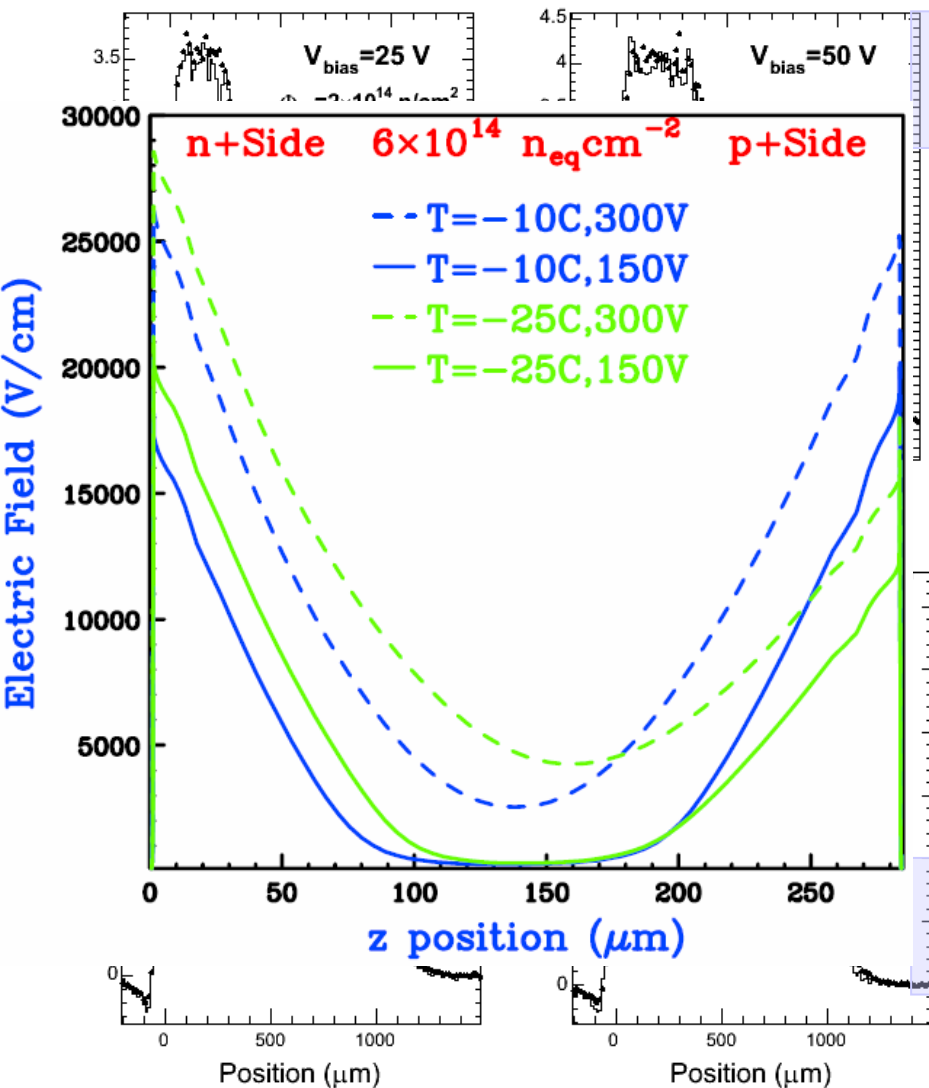
Space charge profile



- Space charge density uniform before irradiation
- Current conservation and non uniform carrier velocities produce a non linear space charge density after irradiation
- The electric field peak at the p+ backplane increases with irradiation

V.Chiochia, M.Swartz,et al.,physics/0506228

Temperature dependence

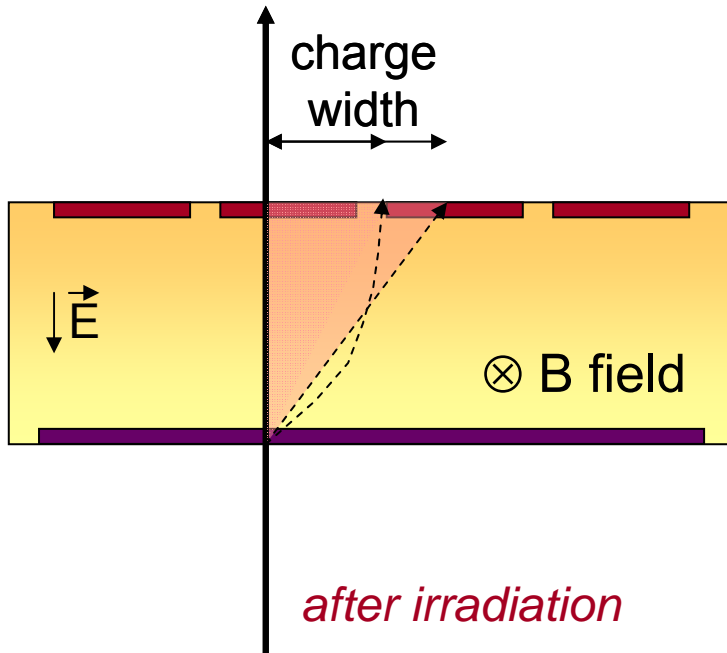


- Comparison with data collected at lower temperature $T = -25^\circ \text{ C}$.
- Use temperature dependent variables:
 - recombination in TCAD
 - variables in PIXELAV
- The double-trap model is predictive!

V.Chiochia, M.Swartz, et al., physics/0510040

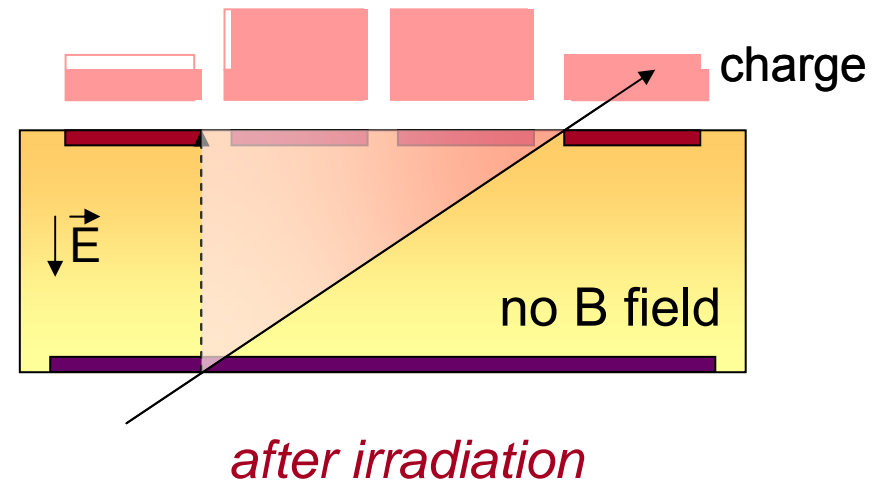
Impact on reconstruction

r- ϕ plane



Irradiation modifies
the electric field profile:
varying Lorentz deflection

r-z plane



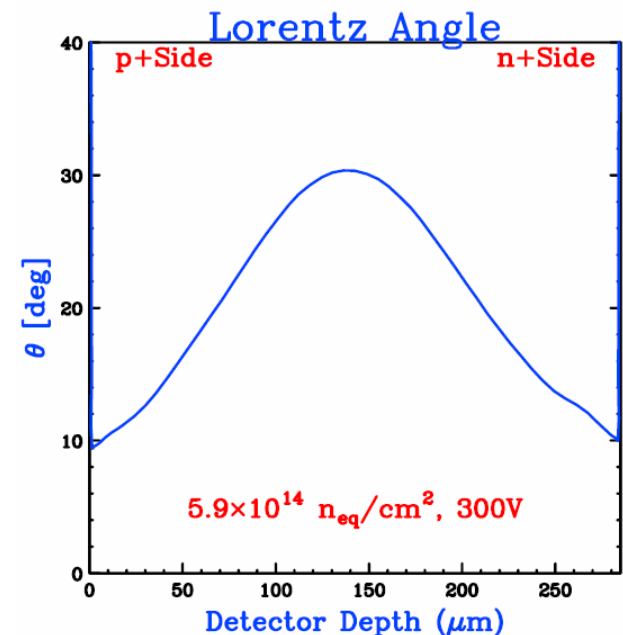
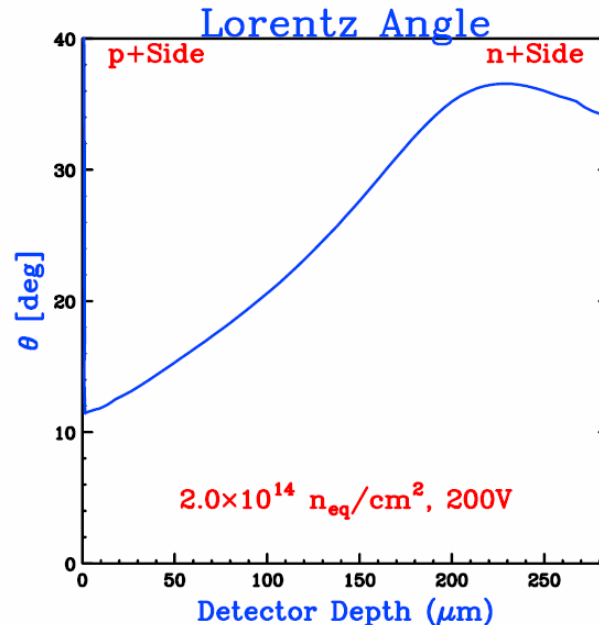
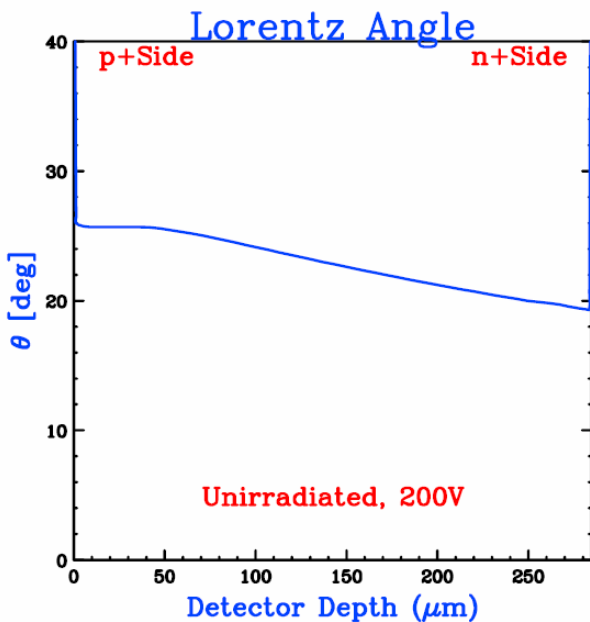
Irradiation causes
charge carrier trapping

Lorentz deflection



Switching on the magnetic field:

$$\tan(\theta) \text{ linear in the carrier mobility } \mu(E): \tan \theta_L = r_H \mu(\vec{E}) B \sin \theta_{vB}$$



LHC startup

2 years LHC low luminosity

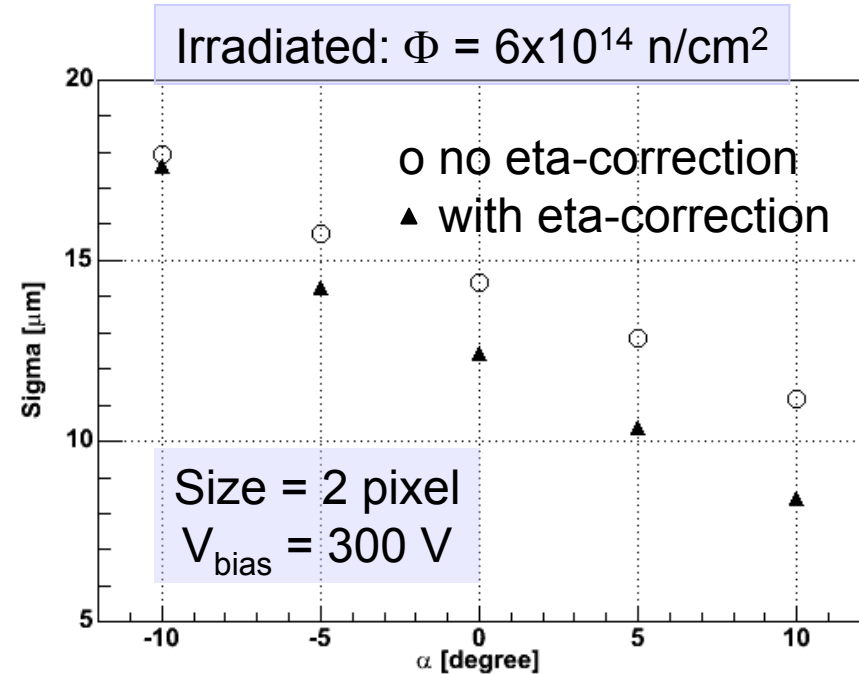
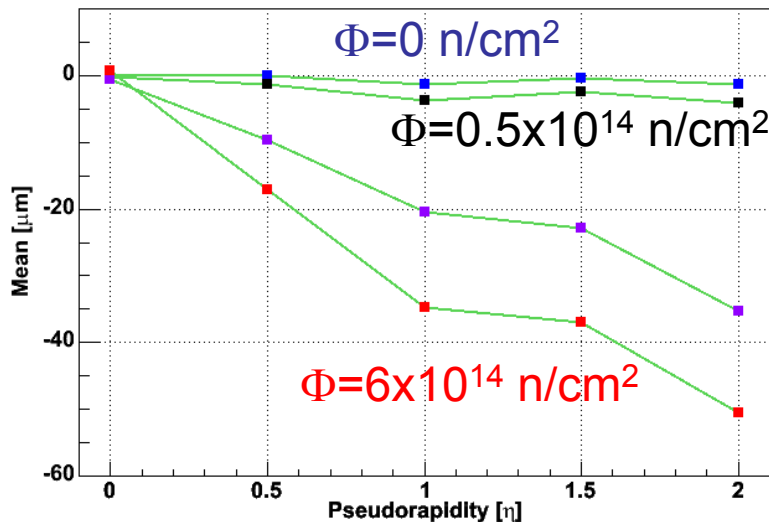
2 years LHC high luminosity

The Lorentz angle can vary a factor of 3 after heavy irradiation:
This introduces strong non-linearity in charge sharing

Position resolution



- Position resolution along the r - ϕ coordinate from simulation
- Pitch = 100 μm , Lorentz effect
- Before irradiation:
 - Size = 2, $\alpha=0^\circ \rightarrow \sigma \sim 9 \mu\text{m}$
- After irradiation ($6 \times 10^{14} \text{ n/cm}^2$)
 - Size = 2, $\alpha=0^\circ \rightarrow \sigma \sim 12 \mu\text{m}$
- Eta corrections can improve resolution after irradiation!



- z (longitudinal) coordinate: residuals mean along the z coordinate vs. pseudorapidity
- Large systematic shifts after irradiation!

E.Alagöz et al., physics/0512027

- After heavy irradiation trapping of the leakage current produces electric field profiles with two maxima at the detector implants. The space charge density across the sensor is not uniform, only ~half of the junction type-inverts.
- What is the meaning of V_{dep} , depletion depth and type inversion? Measurements reflecting the electric field profile (e.g. TCT, CCE, long clusters etc.) are preferable to C-V characterization to understand radiation damage in running detectors
- A physical model based on two defect levels can describe the charge collection profiles measured with irradiated pixel sensors in the whole range of irradiation fluences relevant to LHC operation
- Our model is an “effective theory”: e.g. in reality there are several trap levels in the silicon band gap after irradiation. However, it is suited for calibration and software development related to silicon detectors at LHC.
- We are currently using the PIXELAV simulation to develop hit reconstruction algorithms and calibration procedures optimized for irradiated pixel sensors.

■ PIXELAV simulation:

- M.Swartz, “CMS Pixel simulations”, *Nucl.Instr.Meth.* A511, 88 (2003)

■ Double-trap model:

- V.Chiochia, M.Swartz et al., “Simulation of Heavily Irradiated Silicon Pixel Sensors and Comparison with Test Beam Measurements”, *IEEE Trans.Nucl.Sci.* 52-4, p.1067 (2005), eprint:physics/0411143
- V. Eremin, E. Verbitskaya, and Z. Li, “The origin of double peak electric field distribution in heavily irradiated silicon detectors”, *Nucl. Instr. Meth.* A476, pp. 556-564 (2002)

■ Model fluence and temperature dependence:

- V.Chiochia, M.Swartz et al., “A double junction model of irradiated pixel sensors for LHC”, accepted for publication on *Nucl. Instr. Meth.A*, eprint:physics/0506228
- V.Chiochia, M.Swartz et al., “Observation, modeling, and temperature dependence of doubly-peaked electric fields in silicon pixel sensors”, Accepted for publication on *Nucl. Instr. Meth.A*, eprint:physics/0510040